

Optical technologies, screen resolution and PSF

‘Scintillation Screens and Optical Technology
for transverse Profile Measurements’



ARIES-ADA topical workshop,
Krakow
1-3 April 2019



Stephen Gibson

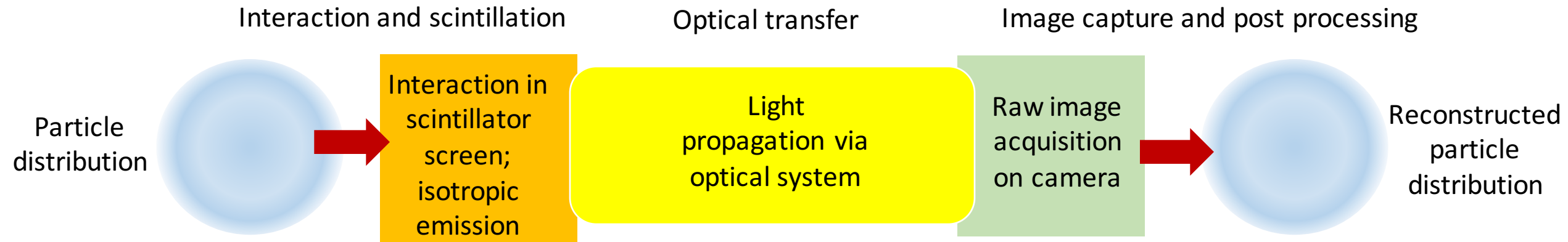
John Adams Institute for Accelerator Science
Royal Holloway, University of London, UK

Outline

- **Motivation: what's the challenge?**
- **Optical technologies**
 - Scintillator-camera geometries
 - Depth-of-field & Scheimpflug principle
 - Avoiding aberrations, key components
 - Telecentric lenses, filters
 - Analytic design and ray tracing
- **Resolution enhancement**
 - Screen thickness
 - PSF and deconvolution
- **Background suppression**
 - OTR, synchrotron light

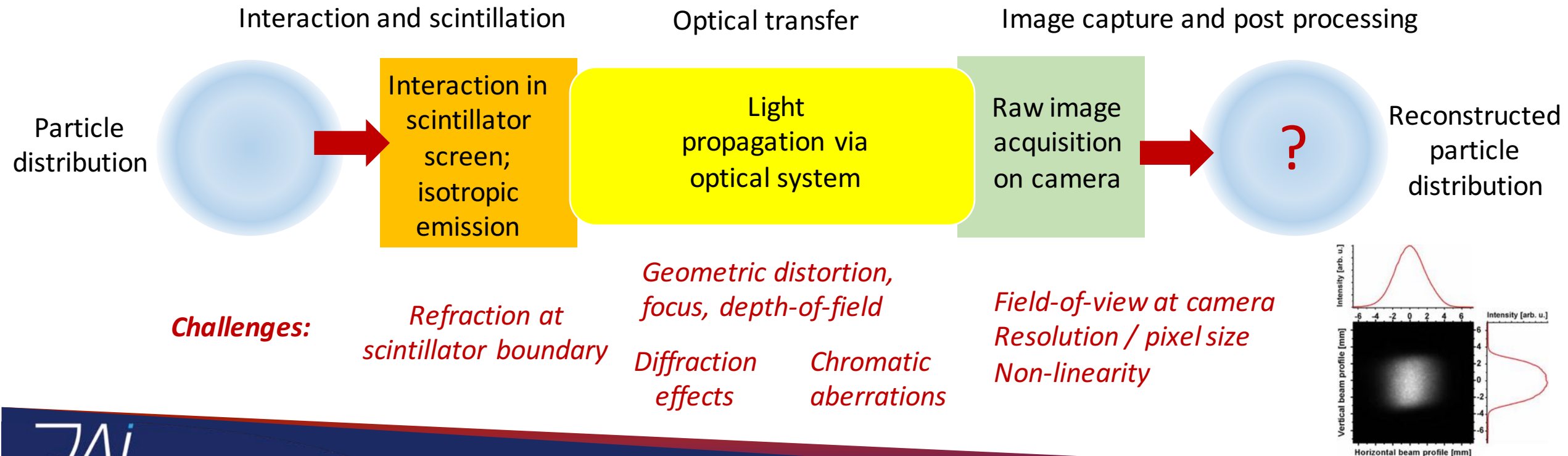
Motivation: what are the challenges when imaging a beam?

- Precise measurements of the **size**, **profile** and **position** of a particle beam striking a scintillator screen requires a carefully designed optical system to transfer scintillation light to the camera, so the true particle distribution can be reconstructed.



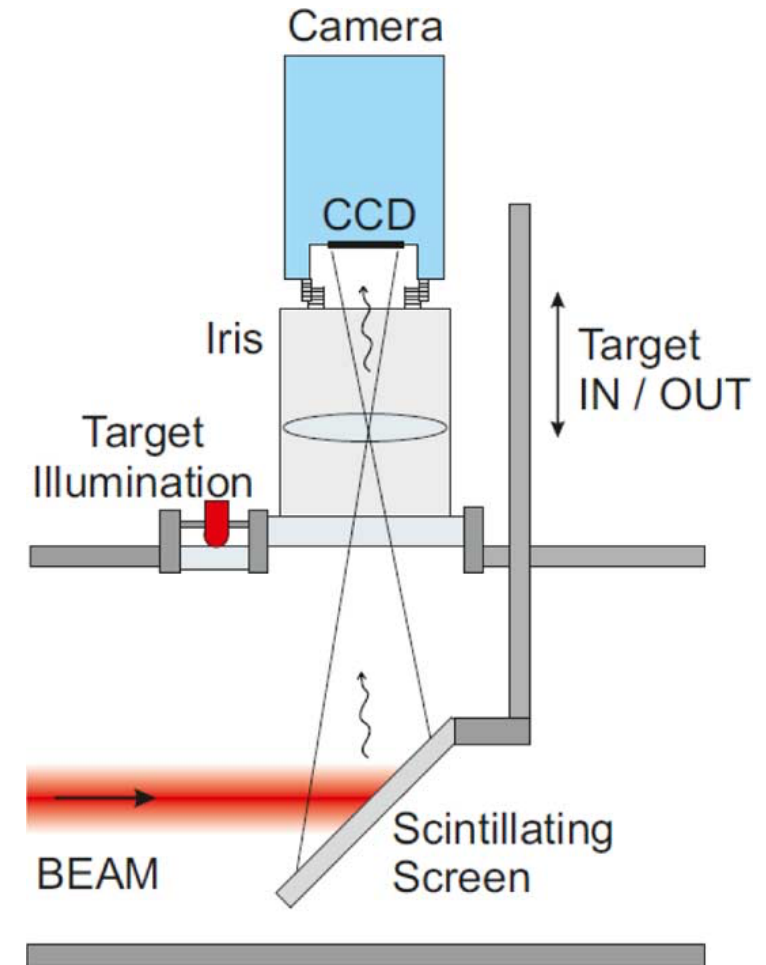
Motivation: what are the challenges when imaging a beam?

- Precise measurements of the **size**, **profile** and **position** of a particle beam striking a scintillator screen requires a carefully designed optical system to transfer scintillation light to the camera, so the true particle distribution can be reconstructed.
- Aim to capture a clean, sharply focused image of the scintillation plane, free of distortion, optical aberrations, non-linearity, or optical backgrounds (OTR).



Scintillator-camera typical setup

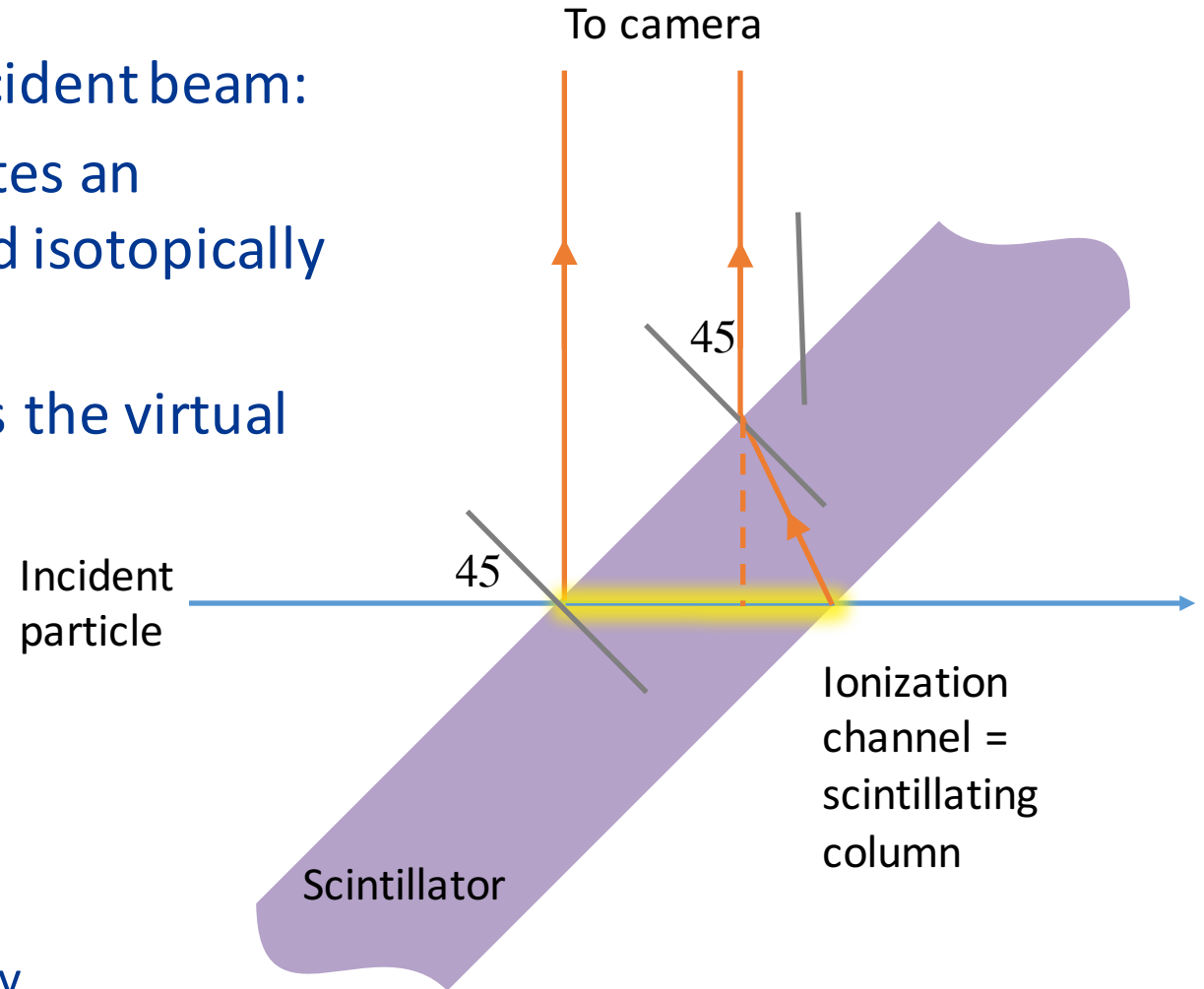
- Particle beam impinges on flat scintillator screen, typically angled at 45 degrees.
- Camera is housed away from beam to reduce radiation, and views the angled screen through a vacuum window.
- A lens (system) is included to form an image of the screen on the sensor plane.
- Include light source to illuminate target.
- Optical Transition Radiation (OTR):
 - Generated by charged particles traversing the vacuum / screen interface and can be reflected towards the camera.
 - Considered here as a background to the scintillation light signal



Walasek-Höhne and G. Kube, Proc. DIPAC'11, Hamburg (Germany), p.553

Light generation and refraction at scintillator-screen

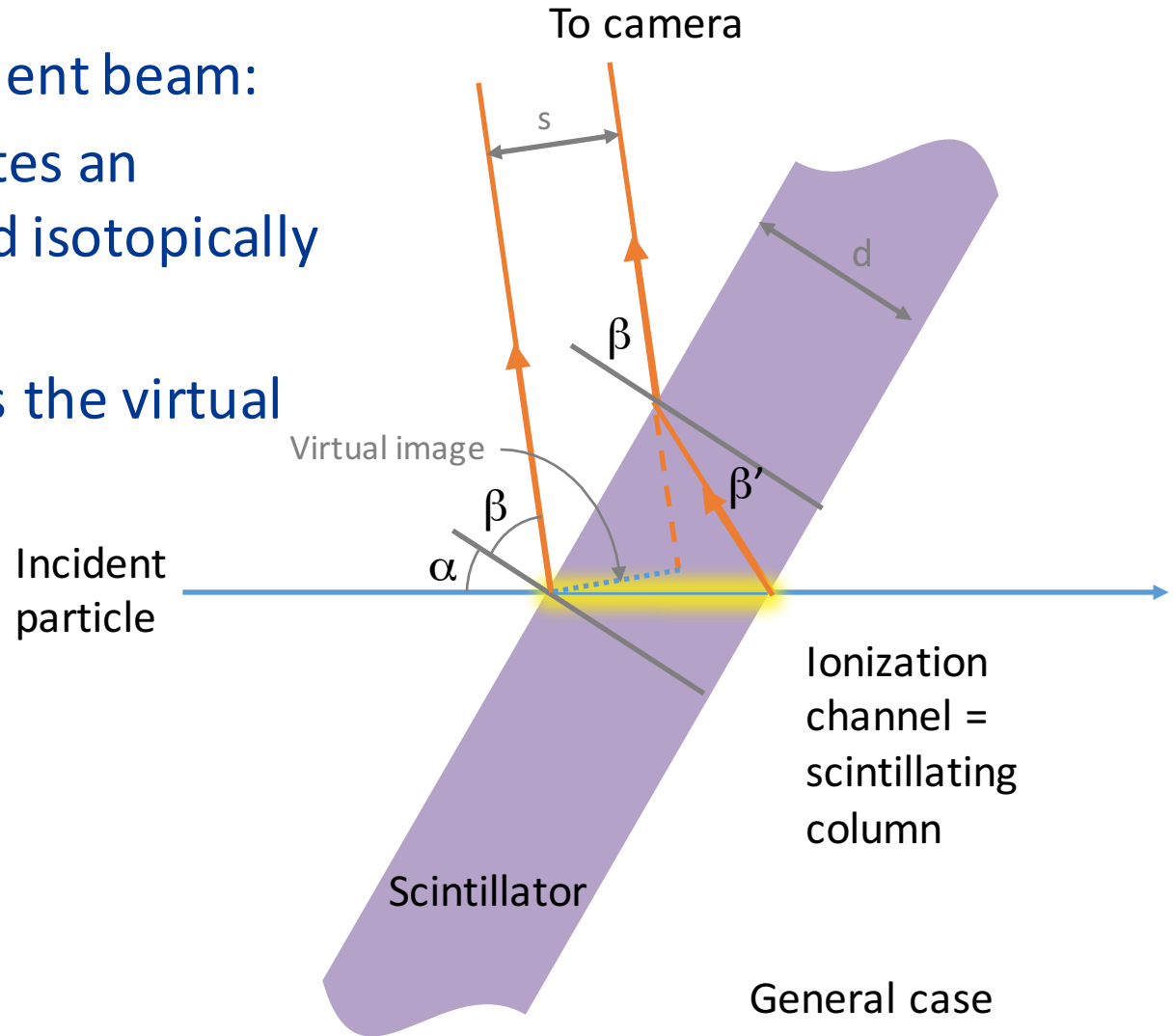
- Consider scintillator screen at angle 45° to incident beam:
- Each particle that crosses the scintillator creates an ionization channel, from which light is emitted isotropically within the volume.
- Refraction of this light at the boundary affects the virtual image size and achievable resolution.
- Scintillator thickness is a trade-off :
 - Thinner screen for best resolution
 - Stability of screen mount, thermal effects.
 - Thicker screen provides more photons.
 - Choice also depends on bunch energy and intensity.



Light generation and refraction at scintillator-screen

- Consider scintillator screen at angle α to incident beam:
- Each particle that crosses the scintillator creates an ionization channel, from which light is emitted isotropically within the volume.
- Refraction of this light at the boundary affects the virtual image size and achievable resolution.

$$s = d \cos \beta \cdot \sqrt{\frac{1}{1 - \frac{\sin^2 \beta}{n^2}} + \frac{1}{\cos^2 \alpha} - 2 \frac{\cos [\arcsin(\frac{\sin \beta}{n}) + \alpha]}{\sqrt{1 - \frac{\sin^2 \beta}{n^2}} \cos \alpha}}$$



See PRSTAB 18 082802 (2015)
(note sign)

Light generation and refraction at scintillator-screen

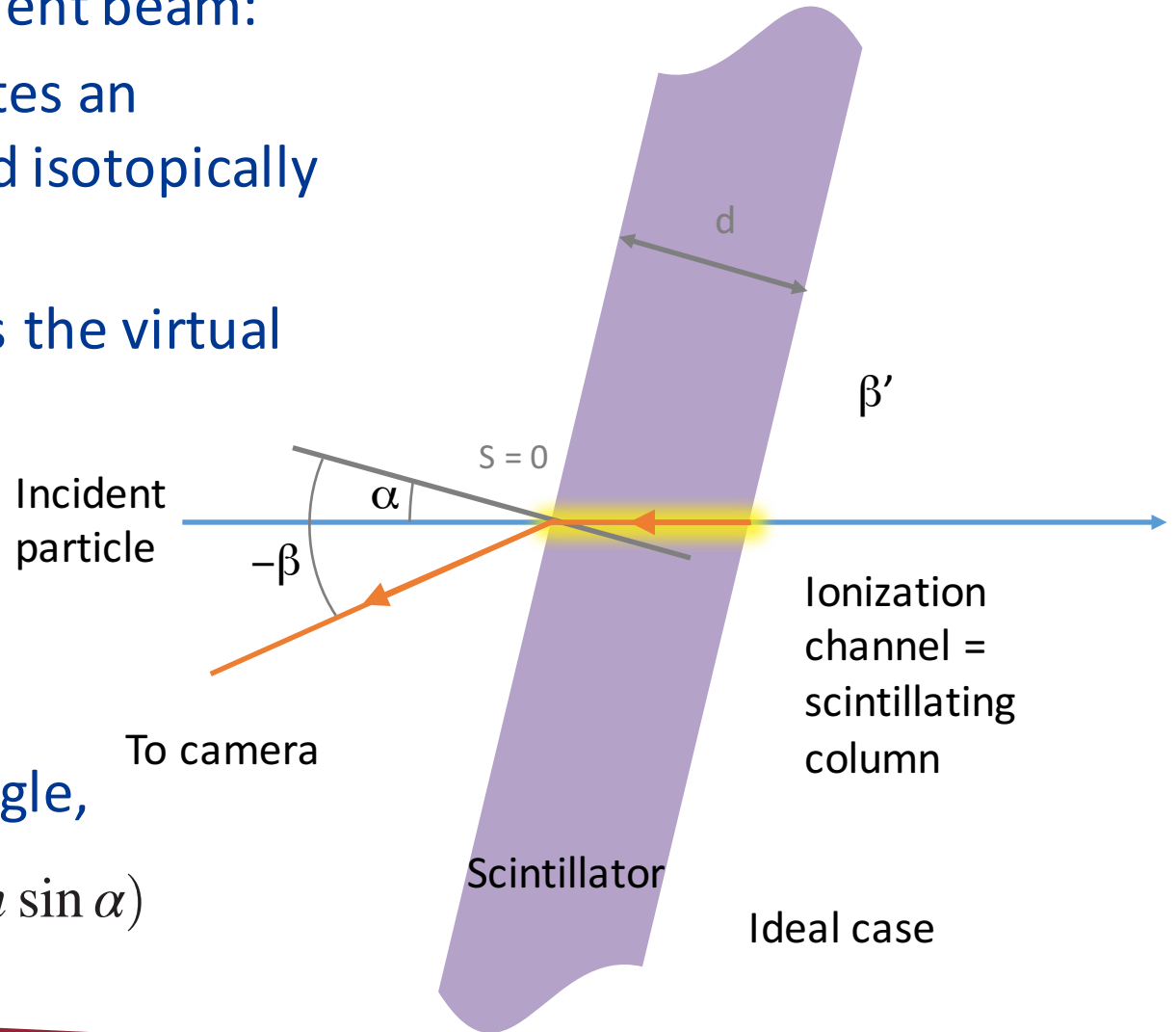
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- Apparent size is zero ($s = 0$) when viewing angle,

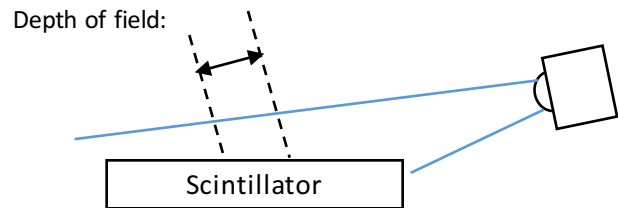
See PRSTAB 18 082802 (2015)
(note sign)

$$\beta_{\text{ideal}} = -\arcsin(n \sin \alpha)$$



Depth of field

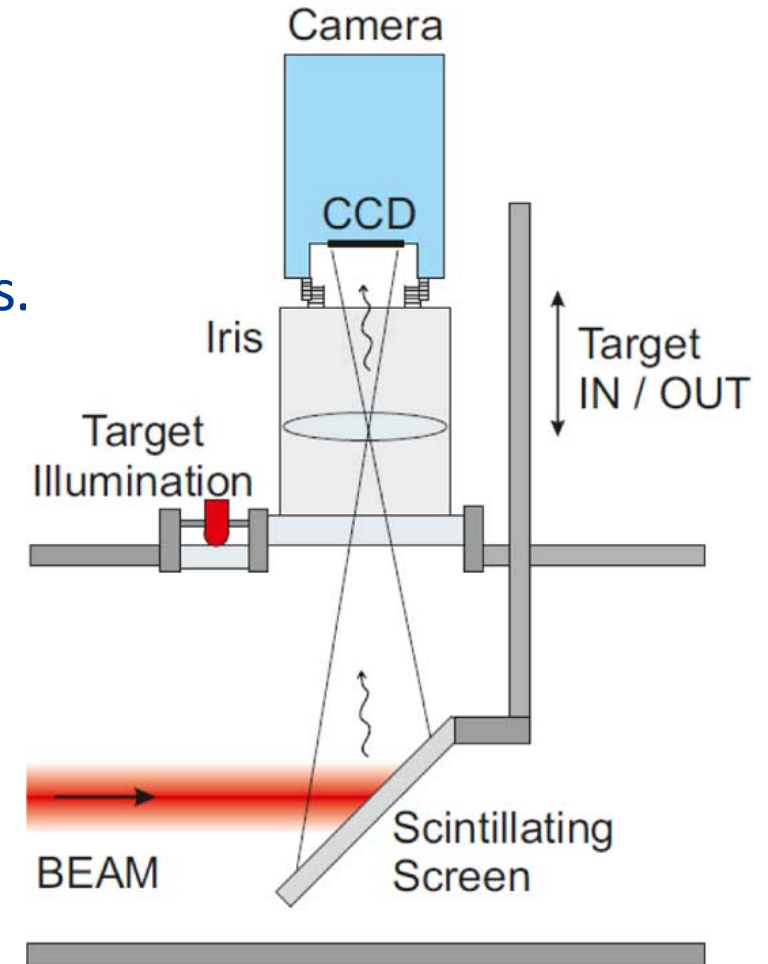
- In the typical setup, the camera-lens must focus on a scintillator plane surface that is at an oblique angle...
- This works for very small electron beams of only $10\ \mu\text{m}$ or so, when the distribution is well within the depth-of-field of the lens.
- However, for larger beams only part of the scintillator plane will be in focus:



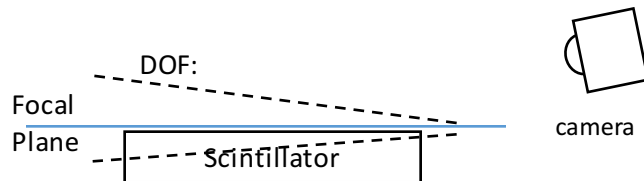
IEEE TRANSACTIONS ON NUCLEAR SCIENCE, VOL. 59, NO. 5, OCTOBER 2012

TABLE I
SIMPLIFIED OVERVIEW OF SCINTILLATOR USAGE IN BEAM
DIAGNOSTICS AND HIGH ENERGY PHYSICS

	Ion Diagnostic	Electron Diagnostic	High Energy Physics
Application	Primary beam on screen Transverse beam profile		Detection of secondary particles, tracking, timing
Particle energy	1 keV – 100 GeV/u	100 keV – 10 GeV	up to 10 GeV
Spot size	1 mm – cm	10 μm – mm	1 cm – 100 cm
Particle rate	very high	very high	low
Dose rate	very high	high	low
Energy deposition	very large	medium	low
Saturation	expected	possible	none
Modification	expected	possible	low



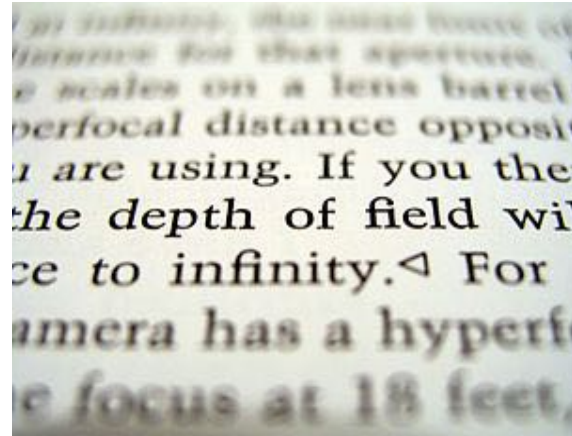
- What we really need is this:



Walasek-Höhne and G. Kube, Proc. DIPAC'11, Hamburg (Germany), p.553

Depth of field: the view camera

How to focus on *all the Wawel wall of Krakow*?

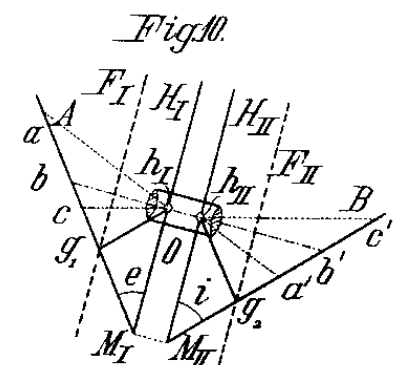


- View cameras can move the lens in x & y tilt, and z translation; and are still made today:

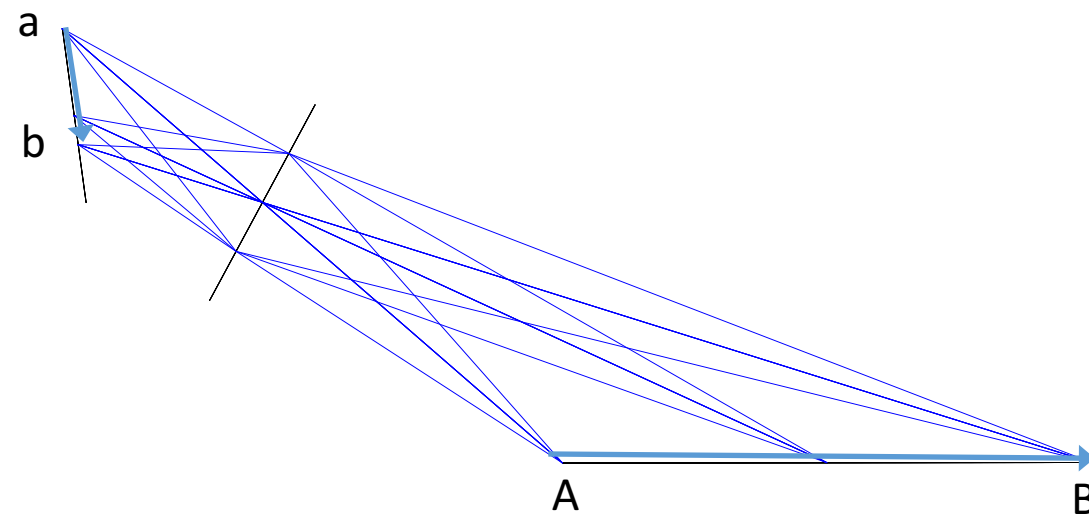
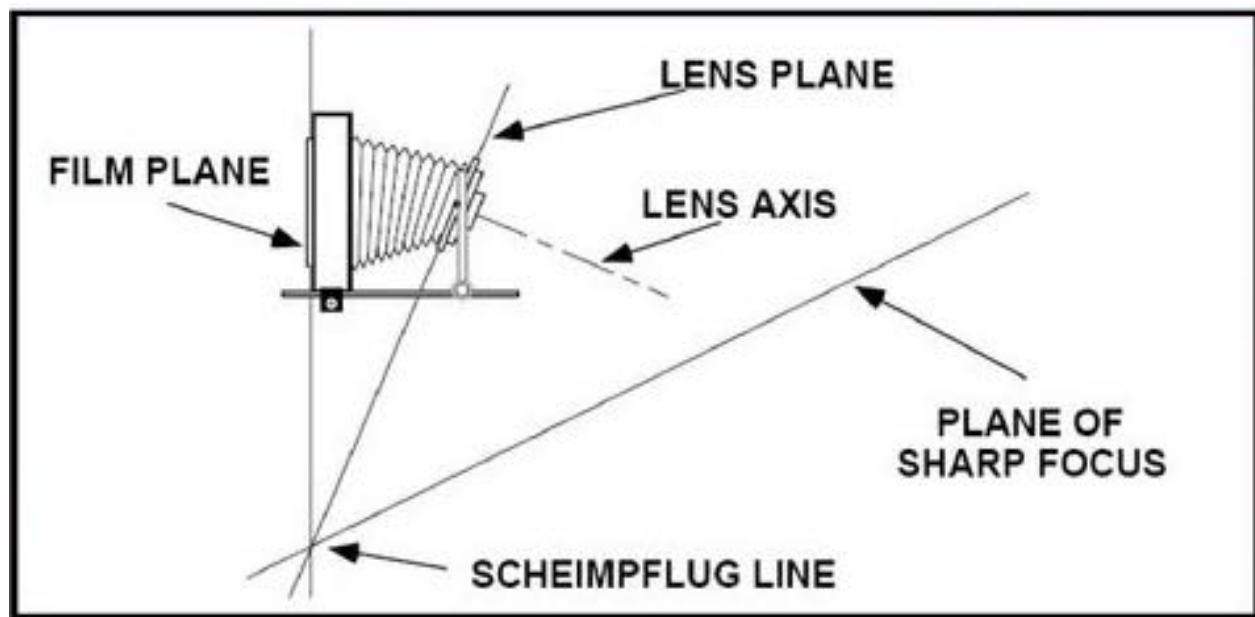
- Fortunately, this is a solved problem in photography and is the basis of the “view camera”



The Schiempflug Principle



- Captain Theodor Scheimpflug was an Austrian Army & Navel officer who used aerial photography to make accurate maps with undistorted images from balloon-suspended cameras (not pointing straight down).
- His principle states that if subject plane, lens plane and image plane intersect in a single line as shown, then the subject plane is completely in sharp focus.



<http://www.trenholm.org/hmmerk/download.html>
https://en.wikipedia.org/wiki/Scheimpflug_principle

Depth of field: the view camera

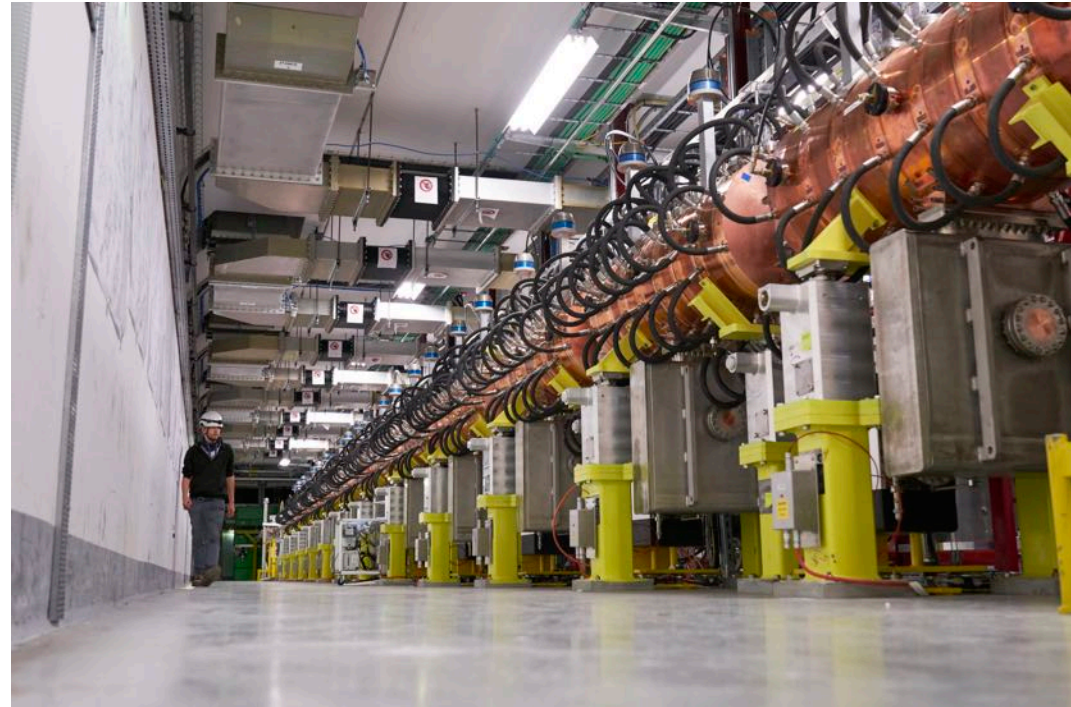
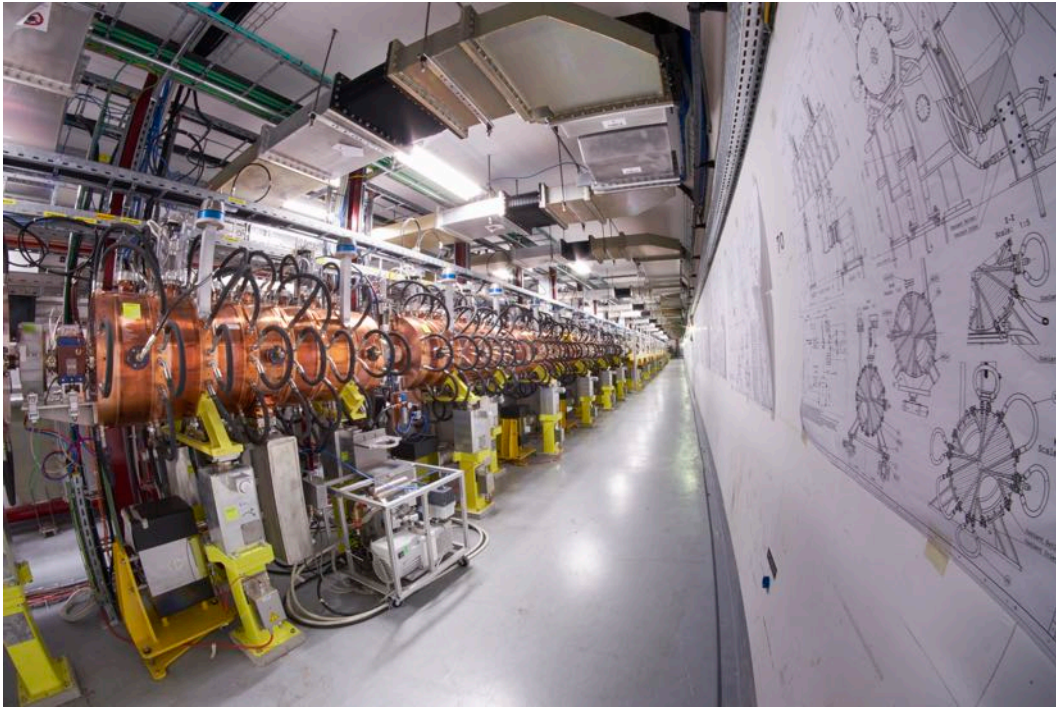


Photo by J-E Nyström, Helsinki, Finland

A modern Scheimpflug mount

MCSM1-01X is a variable macro lens expressly designed for 3D measurement and imaging applications where the object plane is not perpendicular to the optical axis. A precise built-in adjustment mechanism allows the lens to accurately meet the Scheimpflug condition and to image tilted planes in perfect focus. This lens offers a wide range of magnifications and view angles. It can be interface with any structured light source to build up extremely accurate 3D imaging systems. Image sharpness is maintained even when the lens is tilted by a wide angle, since the Scheimpflug adjustment tilts around the horizontal axis of the detector plane. The tiltable mount is compatible with any C-mount camera.

KEY ADVANTAGES

Precision Scheimpflug mount

Image focus is retained across any tilted plane.

Compatible with any C-mount cameras

The back focal length meets the C-mount standard.

Application flexibility

Supports a wide range of magnification factors and viewing angles.

1/3" TO 2/3" SENSORS



 OPTO ENGINEERING

A modern Scheimpflug mount



Example of Scheimpflug beam diagnostic (for OTR)

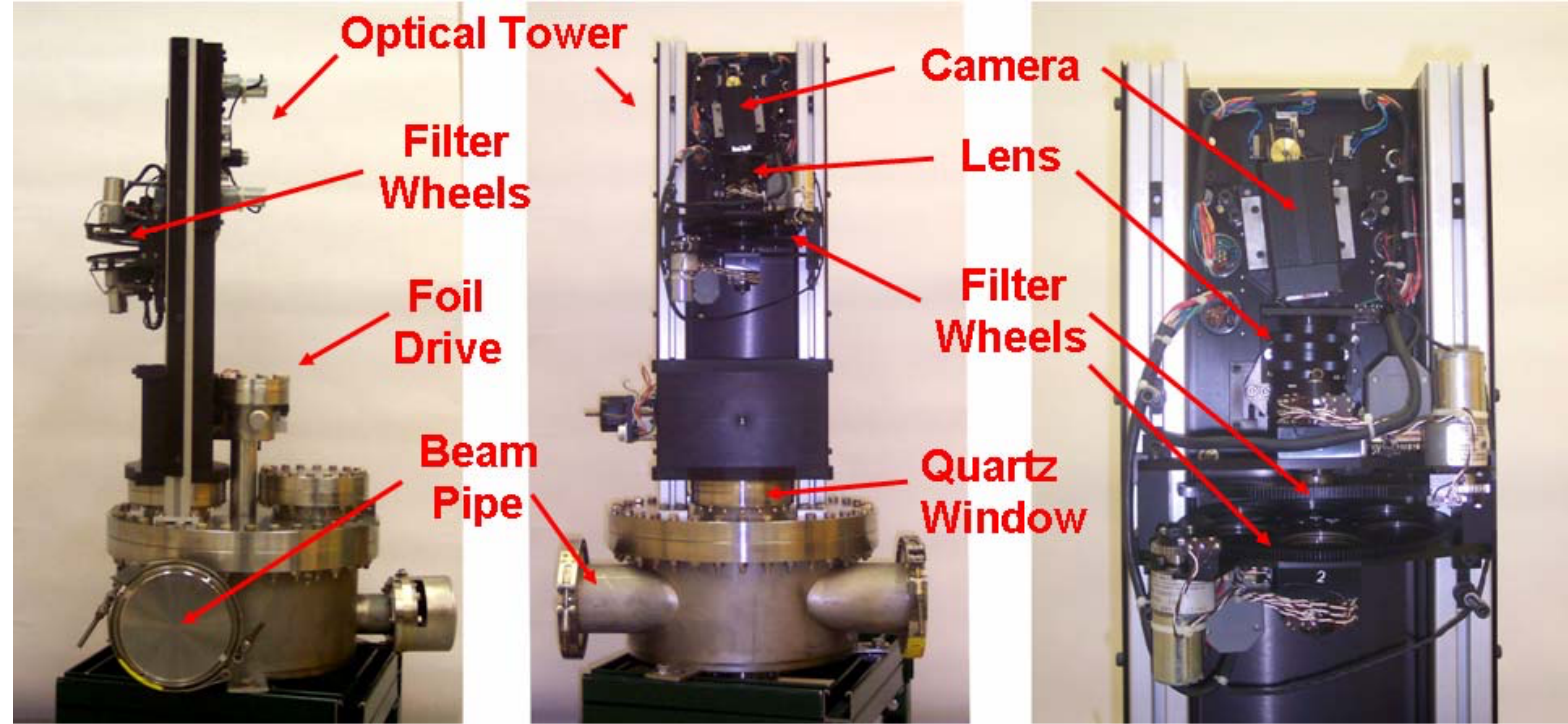
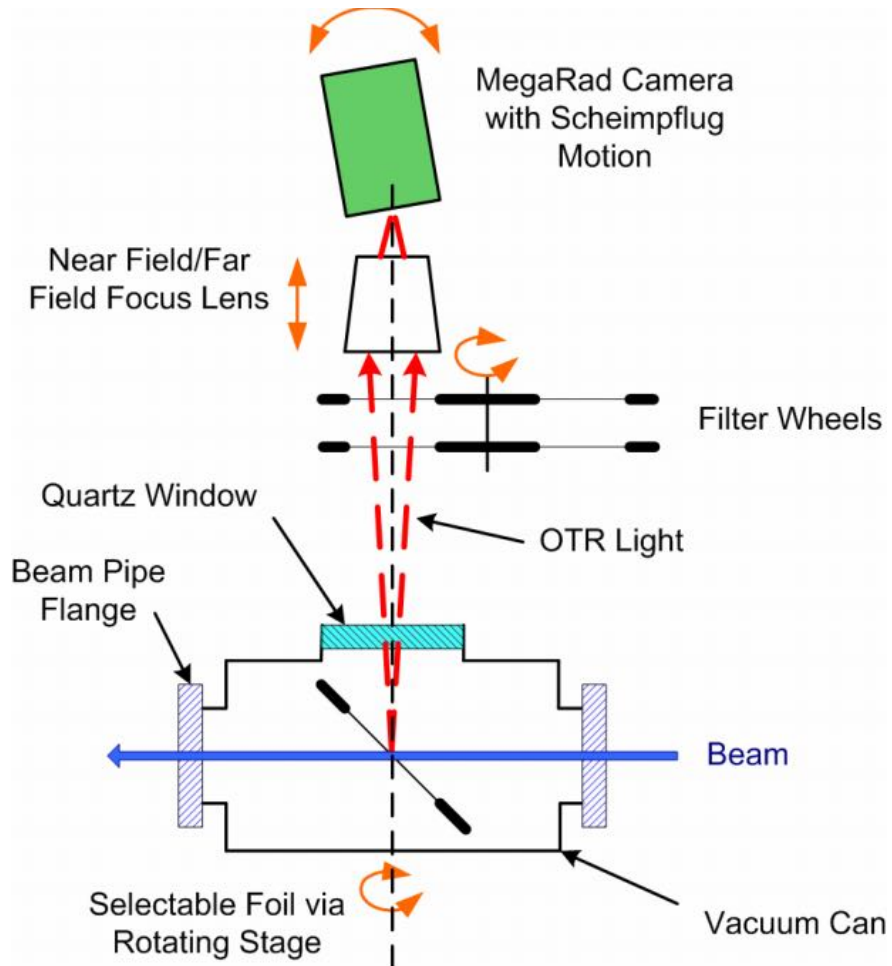


Figure 2: The OTR detector. Left image shows beam line view of detector. Center image shows side of detector. Right image shows magnified view of optical tower with camera, lens and filter wheel assembly.

V. Scarpine, Proc of PAC 2005

Common scintillator layouts

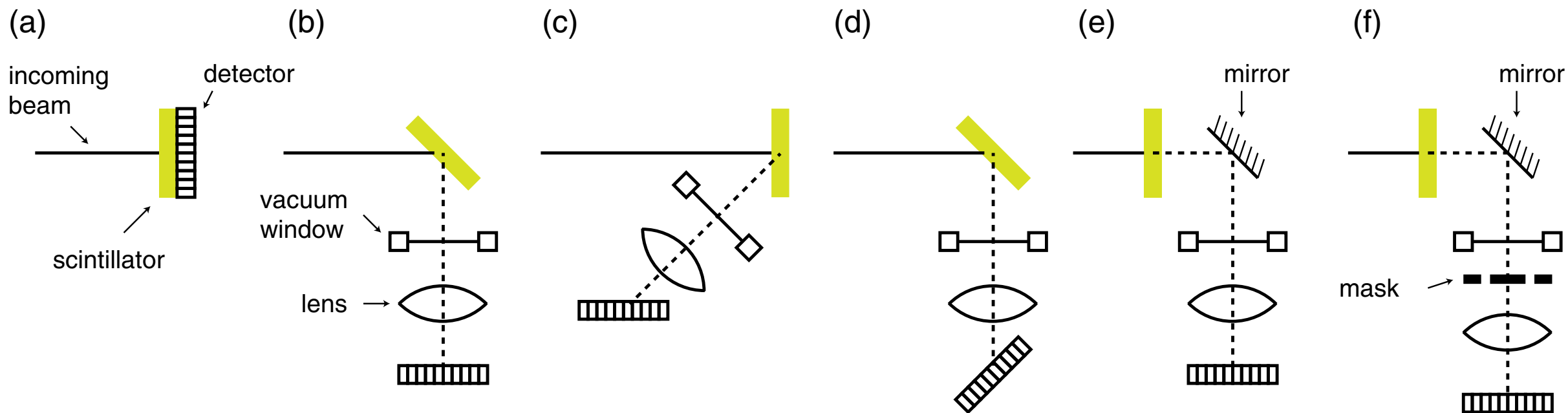


FIG. 1. Commonly used layouts to image fluorescent light onto a detector. (a) Direct detection of the light, (b) and (c) imaging the light through a vacuum window, (d) observing the Scheimpflug imaging geometry, (e) using an additional in-vacuum mirror, and (f) with an additional mask to block coherent transition radiation.

PRSTAB 18 082802 (2015)

Optical design with ray tracing software

- Ray tracing divides the real light field into discrete monochromatic rays that are propagated through the system. Can input real light distribution.
- Several professional software suites available, e.g.

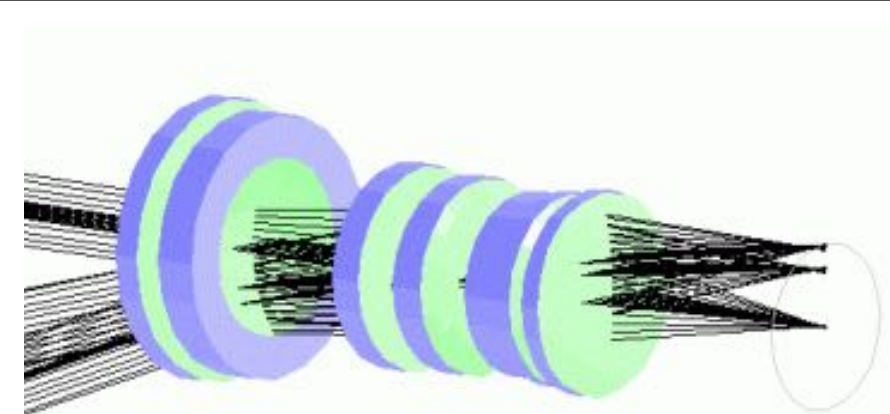
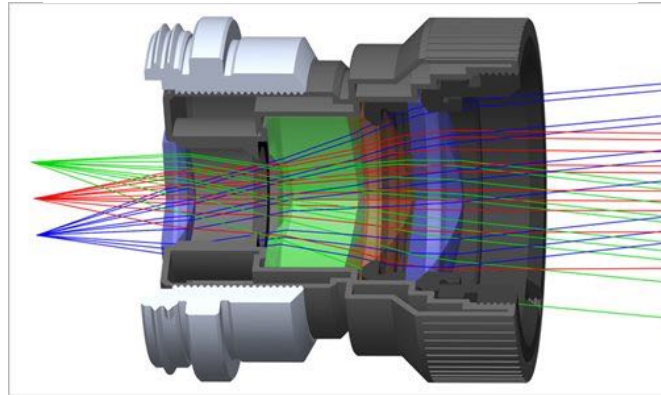
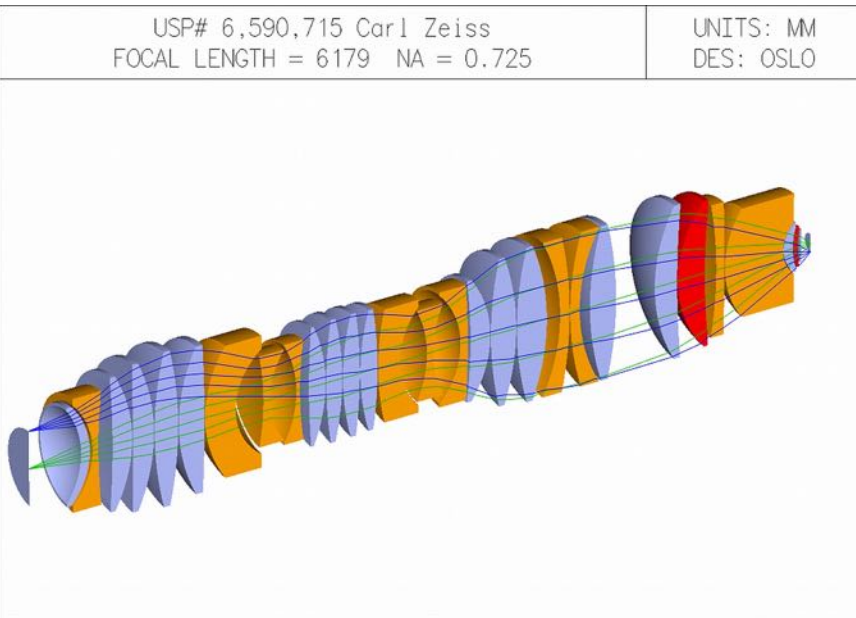
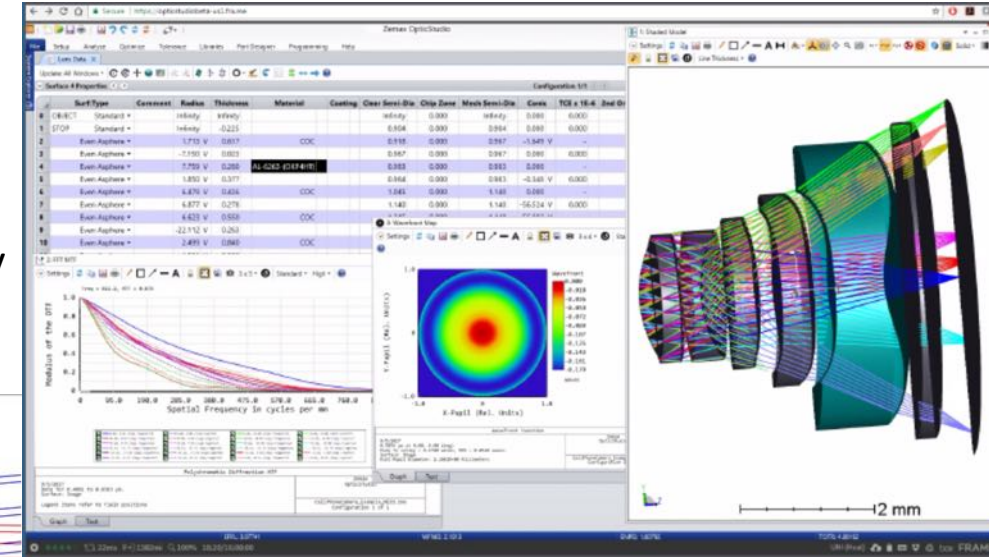
OSLO: Optics Software for Layout and Optimization

<https://www.lambdares.com/oslo/>

ZEMAX

<https://www.zemax.com/>

LensMechanix®

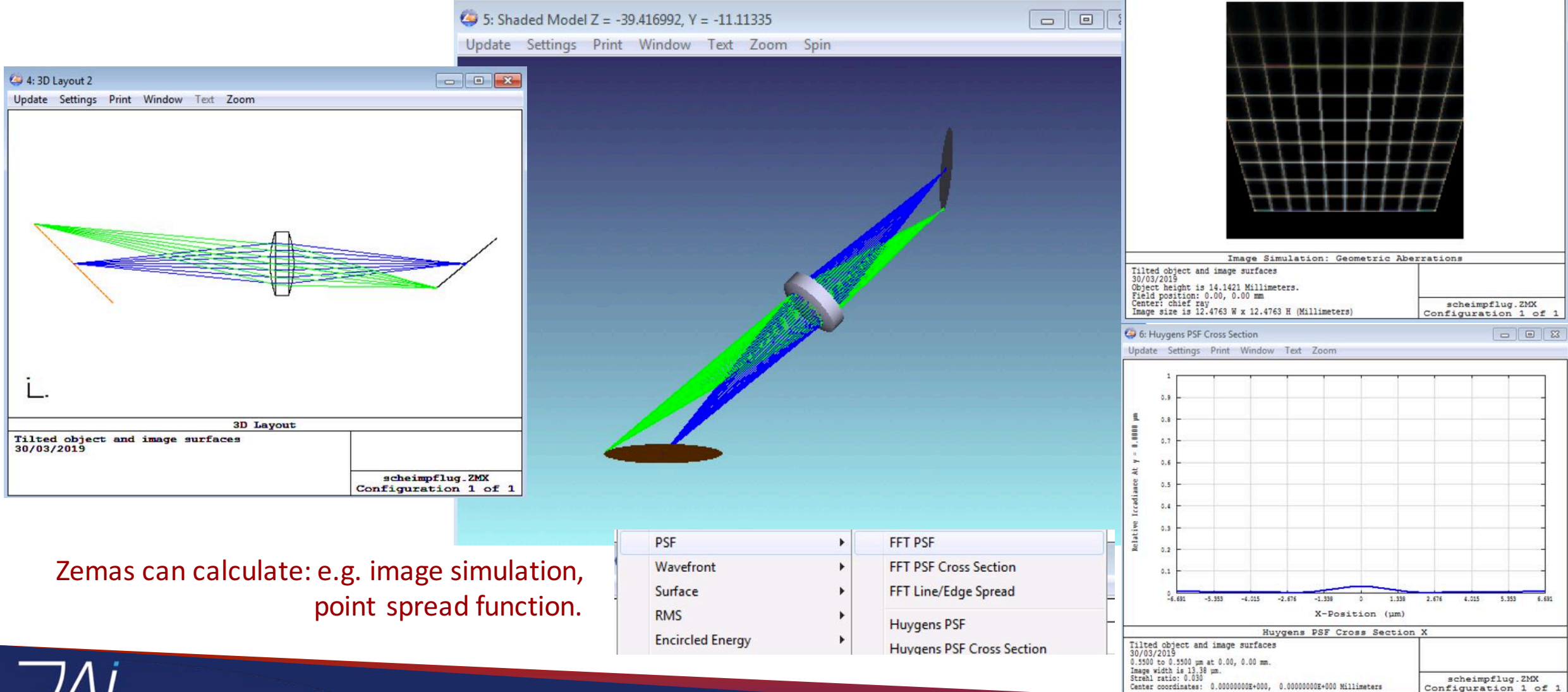


WinLens3D - lens design & optimization software

http://www.opticalsoftware.net/index.php/how_to/lens_design_software/winlens3d/

e.g. Scheimpflug principle in Zemax

- Tilted object and image planes with respect to lens



The screenshot displays four windows from the Zemax software interface:

- 4: 3D Layout 2:** Shows a 2D ray diagram of a lens system with a tilted object and image plane.
- 5: Shaded Model Z = -39.416992, Y = -11.11335:** Shows a 3D perspective view of the lens and the tilted object and image planes.
- 6: Image Simulation:** Shows a grid of light rays forming a trapezoidal shape, representing the image simulation.
- 6: Huygens PSF Cross Section:** Shows a graph of Relative Irradiance vs. X-Position (μm).

Image Simulation: Geometric Aberrations

Tilted object and image surfaces
 30/03/2019
 Object height is 14.1421 Millimeters.
 Field position: 0.00, 0.00 mm
 Center: chief ray
 Image size is 12.4763 W x 12.4763 H (Millimeters)

scheimpflug.ZMX
 Configuration 1 of 1

Huygens PSF Cross Section

Relative Irradiance At y = 0.8000 μm

X-Position (μm)

Huygens PSF Cross Section X

Tilted object and image surfaces
 30/03/2019
 0.5500 to 0.5500 μm at 0.00, 0.00 mm.
 Image width is 13.38 μm.
 Strehl ratio: 0.030
 Center coordinates: 0.00000000E+000, 0.00000000E+000 Millimeters

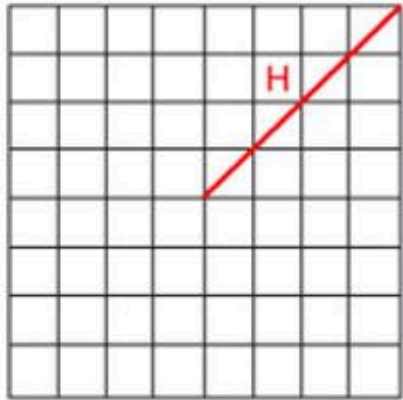
scheimpflug.ZMX
 Configuration 1 of 1

PSF	FFT PSF
Wavefront	FFT PSF Cross Section
Surface	FFT Line/Edge Spread
RMS	Huygens PSF
Encircled Energy	Huygens PSF Cross Section

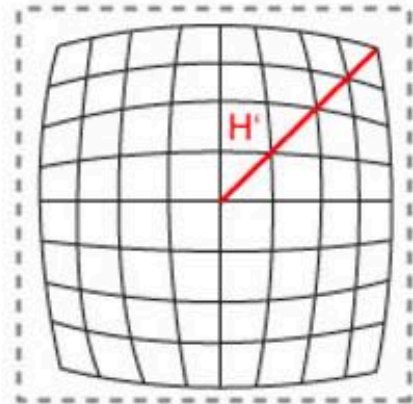
Zemas can calculate: e.g. image simulation, point spread function.

Image distortion

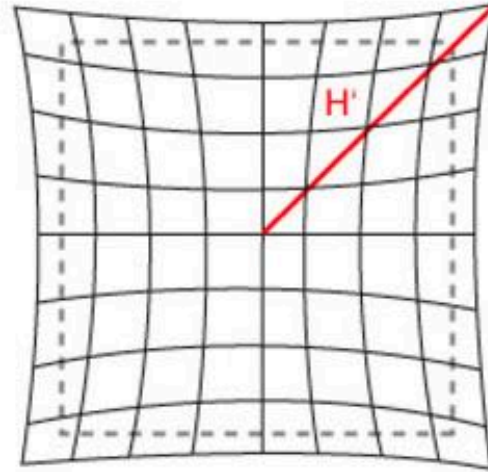
Undistorted Grid



Barrel Distortion (negative)



Pincushion Distortion (positive)



Lens Geometric Distortion Definition

The lens geometric distortion is defined as

$$LGD = 100 \cdot \frac{(H' - H)}{H}$$

H' = dot distance from center of image

H = undistorted dot position

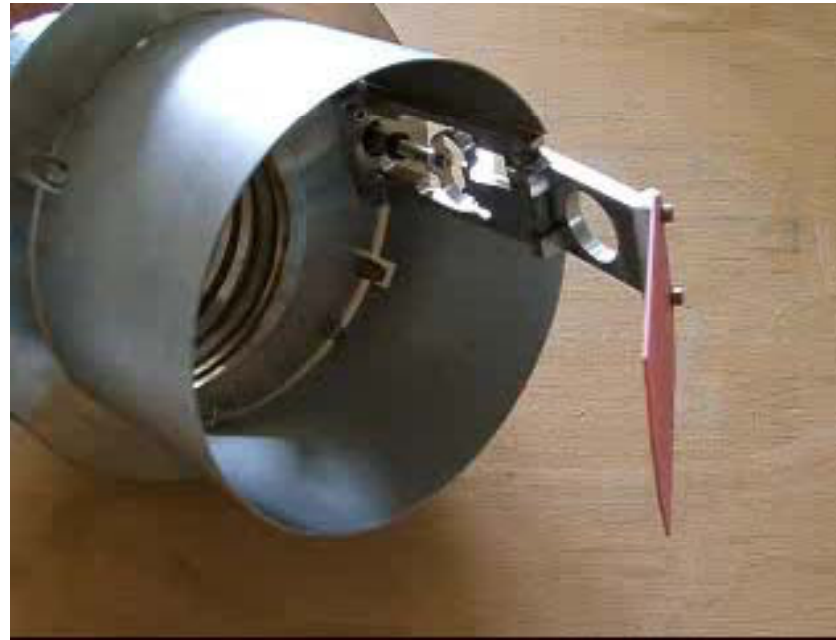
- Barrel distortion: magnification increases with distance from optical axis
- Pincushion distortion: magnification decreases with distance from optical axis



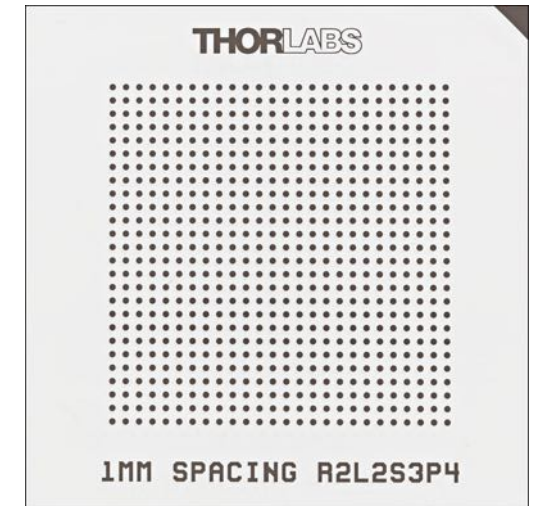
Spotted on a visit to KEK

Scale for calibration of magnification and distortion

- Illuminated target screen with graticule



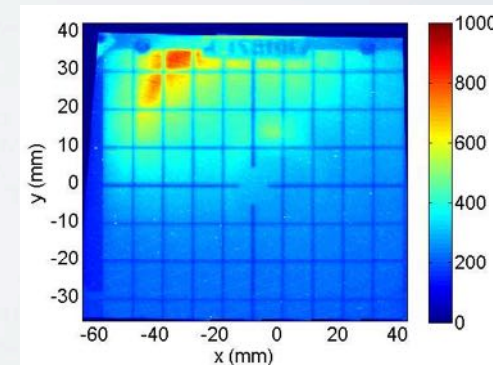
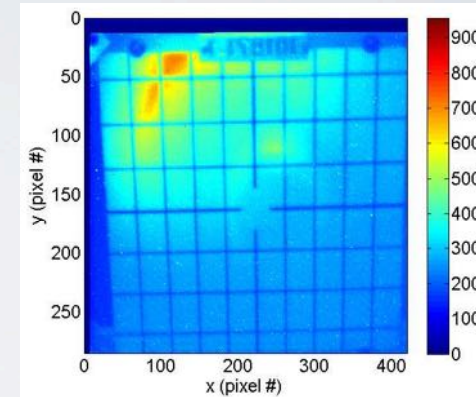
U Raich, CAS Frascati
2008 Beam Diagnostics



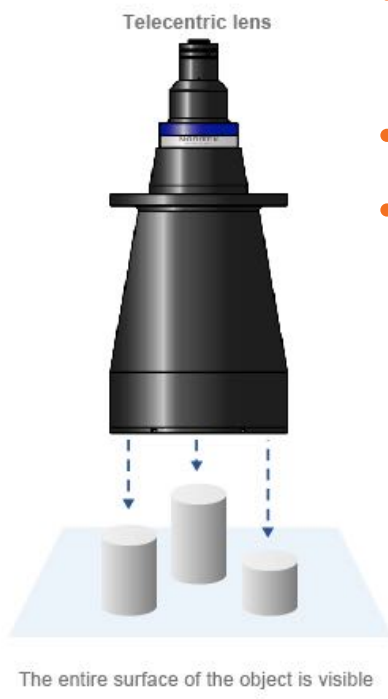
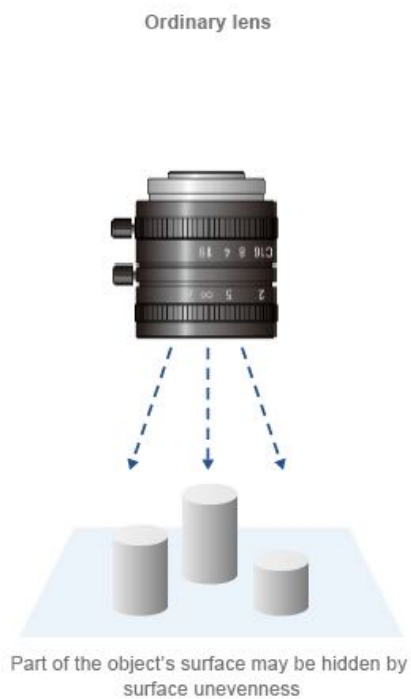
- Image distortion can be calibrated by adding a known network of lines or dots on the target: e.g. keystone (trapezoid) image may be post-processed to compensate for distortion

IMAGE DEFORMATIONS

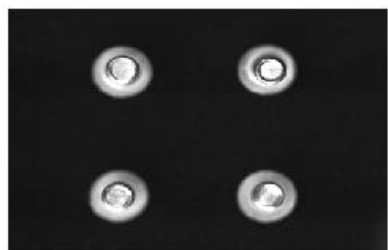
- Usually screens are tilted at 45° or similar
- This introduces the “trapeze” aberration
- Need to calculate and apply a correction algorithm



Enrico Bravin, Proc. of Scintillation workshop at GSI, 2011

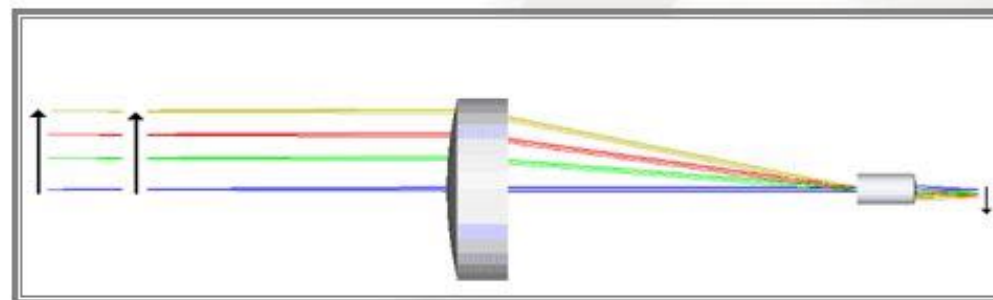


Size of the image changes

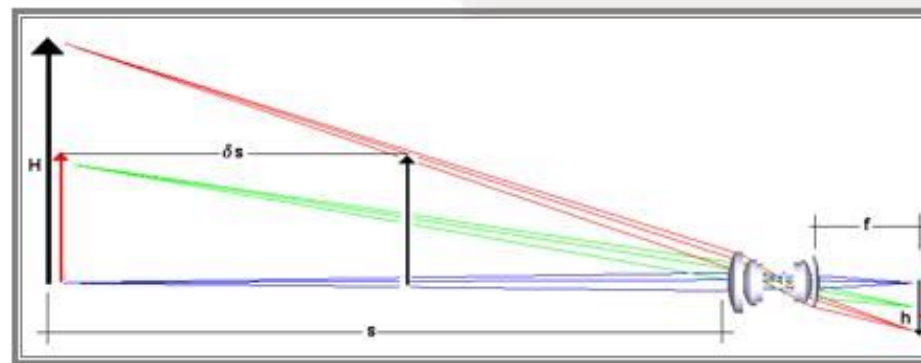


Size of the image remains the same

- Unlike a standard lens, the magnification of a telecentric lens does not change with the object distance.
- Such lenses are often useful in machine vision applications:
- When measuring dimensions, a telecentric lens will yield the same measurement regardless of changes in object distance or position.



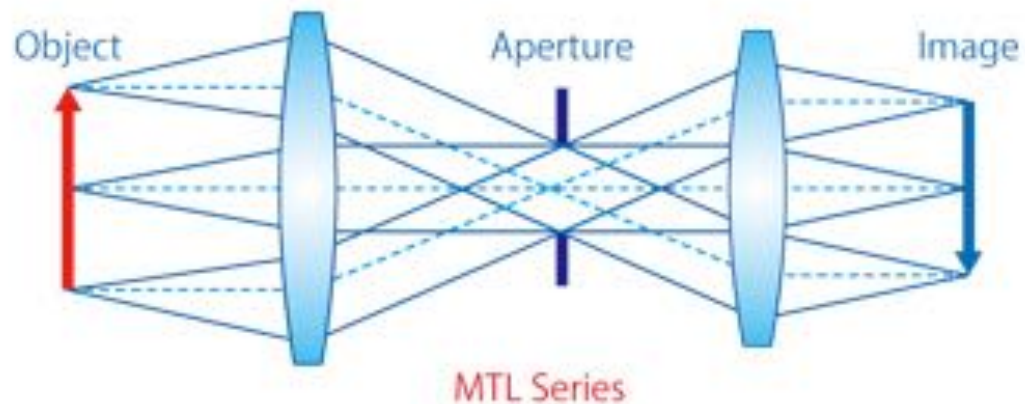
Telecentric Lens



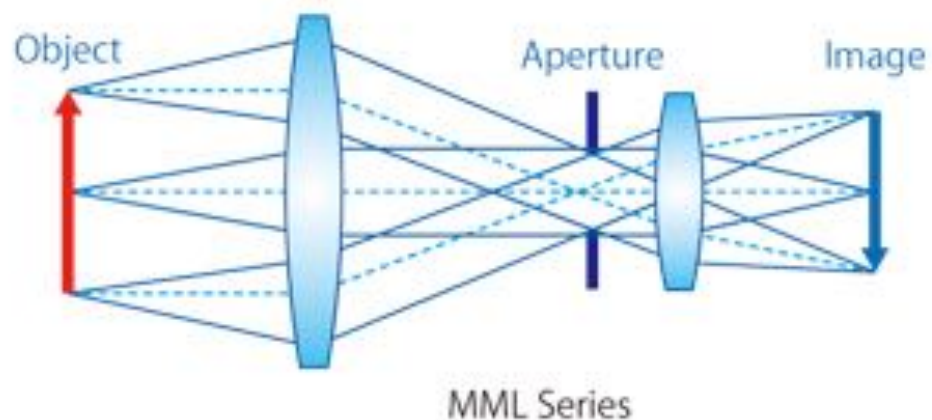
Standard Lens

Bi-telecentric lens with Scheimpflug adjustment

Bi-Telecentric Lens



Object Side Telecentric Lens



- In a bi-telecentric lens, the principle rays are parallel to the optical axis at the object **and** the image.
- Thus the magnification is independent of the object or image distance.
- Can combine this lens with Scheimpflug adjustment:



TCSM080

3D bi-telecentric lens with Scheimpflug adjustment

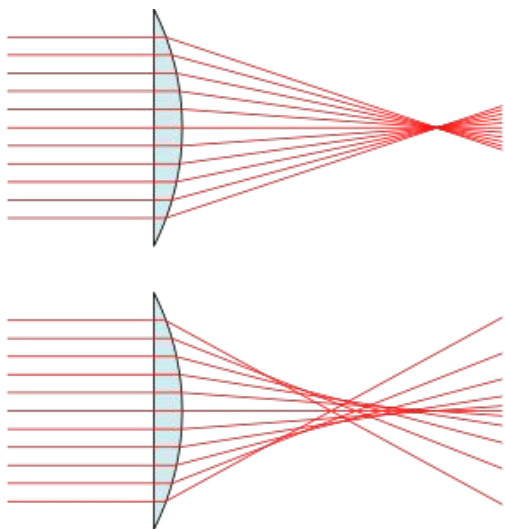
 OPTO ENGINEERING

Other common optical aberrations

- For an ideal optical system, every point in an object space corresponds to a point in image space: a stigmatic image, which typically cannot be perfectly achieved.

- **Spherical aberration:**

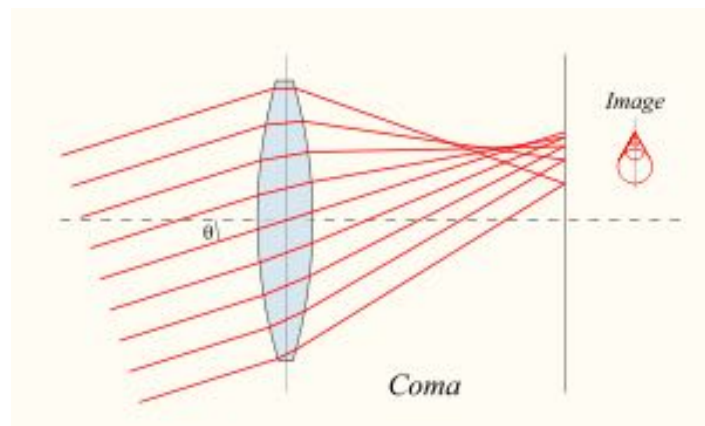
- off axis rays focus at different distances.



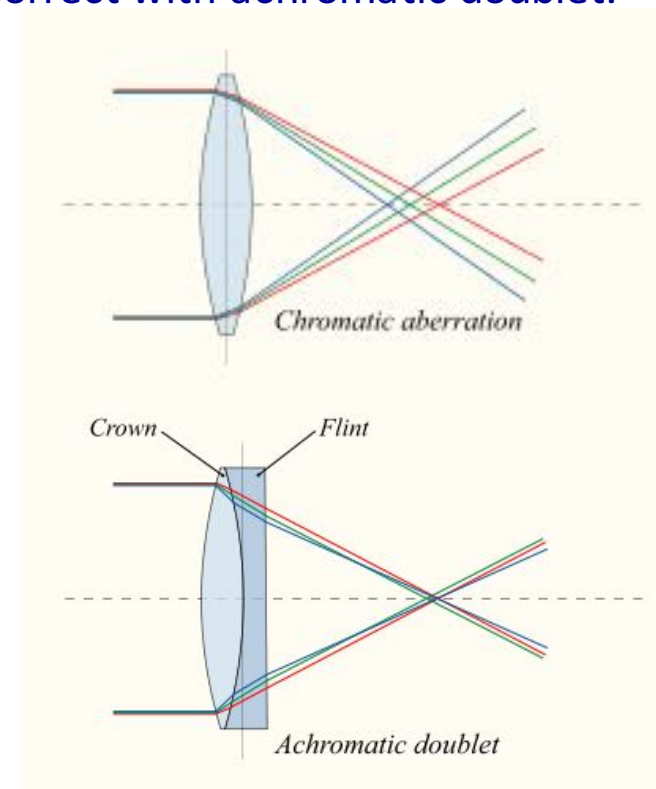
- Can be corrected with Schmitt plate (aspheric lens)

- **Comatic aberration or coma**

- A wavefront distortion appears for object points off-axis: comet like spread.



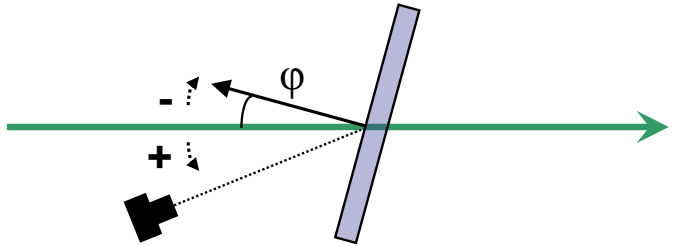
Chromatic aberration: colours refract by different angles due to dispersion. Correct with achromatic doublet.



Screen Resolution: observation geometry

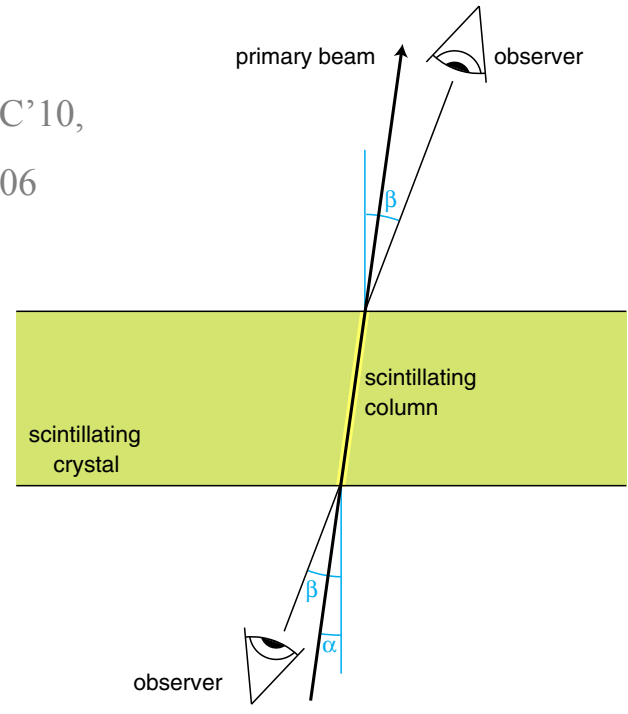
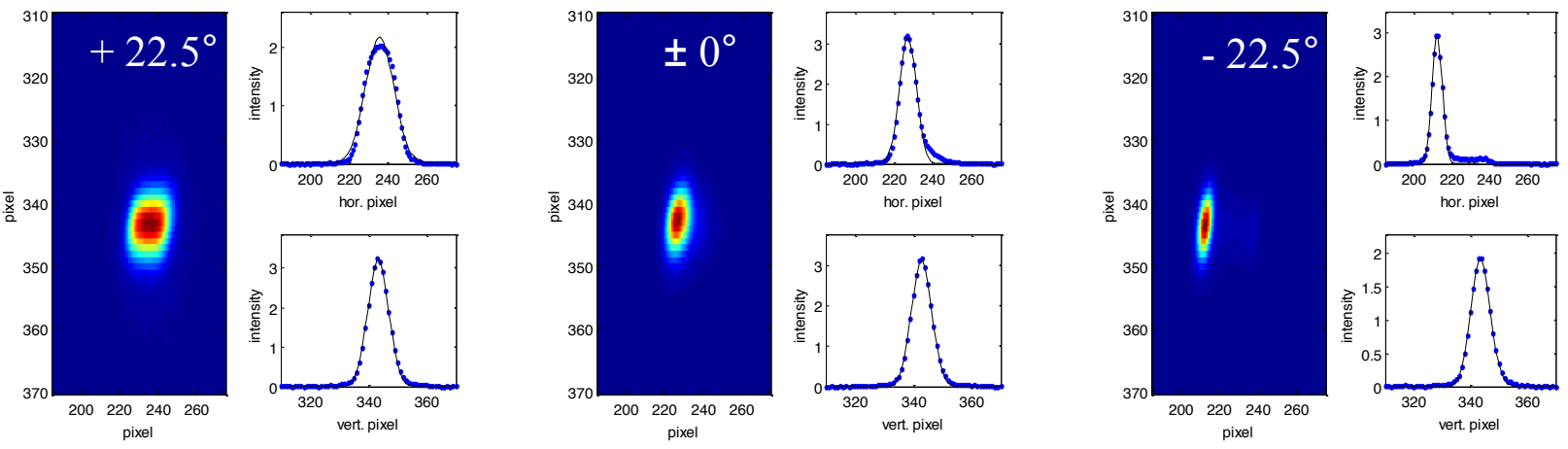
- As we have already seen in Gero's talk this morning, the observation geometry including the tilt of the scintillator and camera wrt the beam axis will strongly influence the **resolution**:

experiment: scintillator tilt vs. beam axis



BGO crystal
micro-focused electron beam
 $I = 3.8 \text{ nA}$

G. Kube et al., Proc. IPAC'10,
Kyoto, Japan (2010), p.906



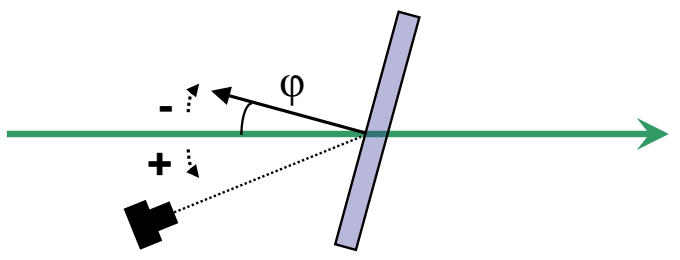
$$\beta_{\text{ideal}} = -\arcsin(n \sin \alpha)$$

PRSTAB 18 082802 (2015)

Screen Resolution: observation geometry

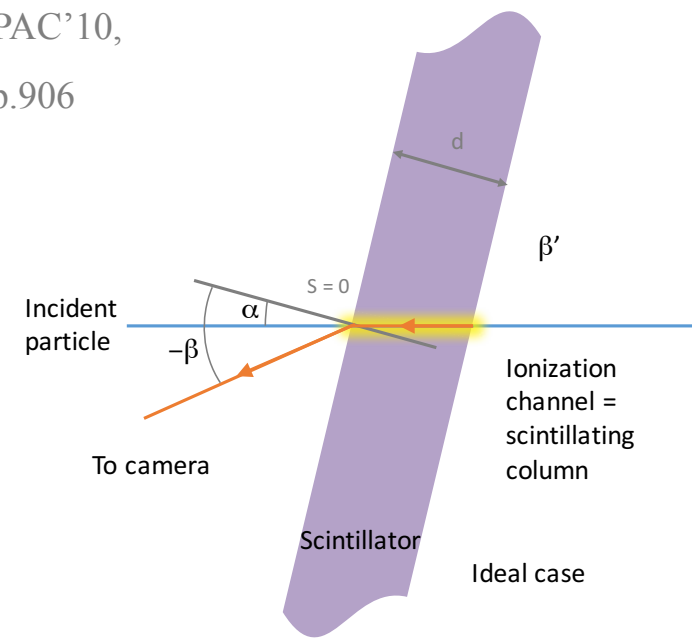
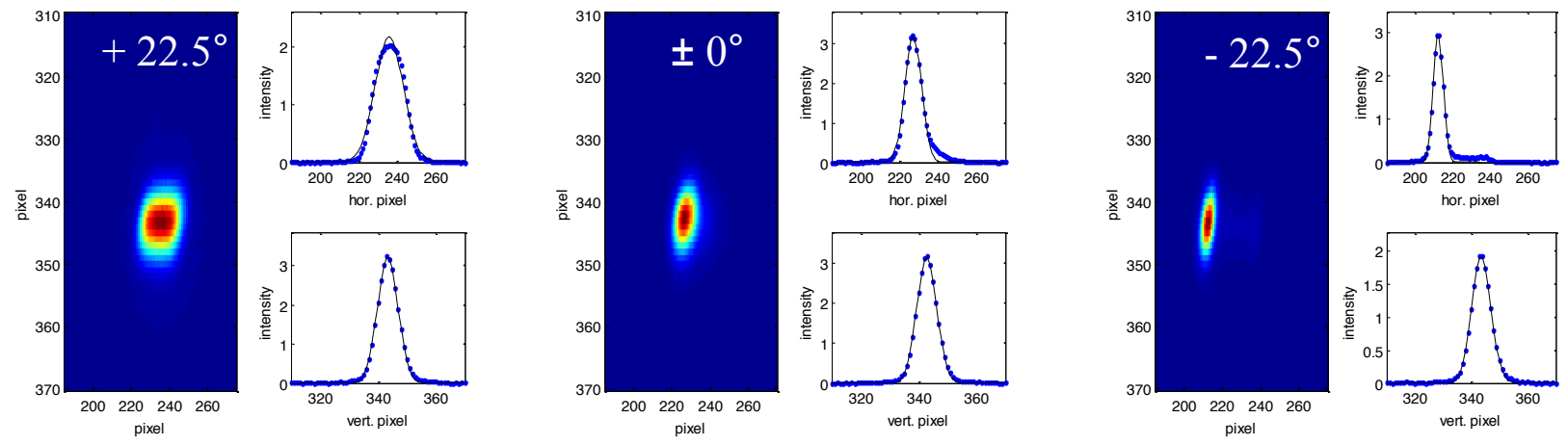
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BGO crystal
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 $I = 3.8 \text{ nA}$

G. Kube et al., Proc. IPAC'10,
Kyoto, Japan (2010), p.906



Ideal case:

$$\beta_{\text{ideal}} = -\arcsin(n \sin \alpha)$$

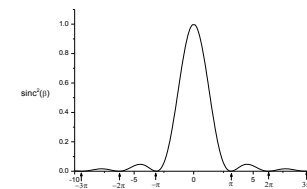
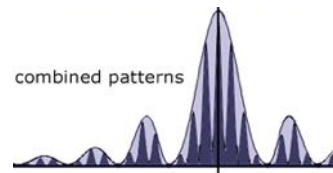
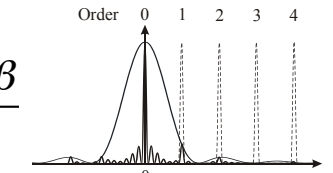
- In addition to observation geometry, the resolution at the image plane will be influenced by diffraction at any restrictive apertures, around bstructions (dust), or aberrations due to lens imperfections or refractive index variations in the optical system.
- An important parameter to determine is the **Point Spread Function (PSF)**: the optical response of the system to a single point of light at the object plane
- In the case of a bunch profile, this is the passage of one charged particle through the scintillator.
- Knowledge of the PSF can be used to the enhance the image resolution.
- But first, a quick reminder on diffractive optics and convolution.

General Fraunhofer Diffraction in 1D

- To calculate the far field diffraction pattern take the **Fourier Transform** of the transmission function of the diffracting aperture:

$$I(\theta_x) = |E_{res}(\theta_x)|^2 = \left| \int_S A(x_s) \exp[-ikx_s \sin \theta_x] dx_s \right|^2$$

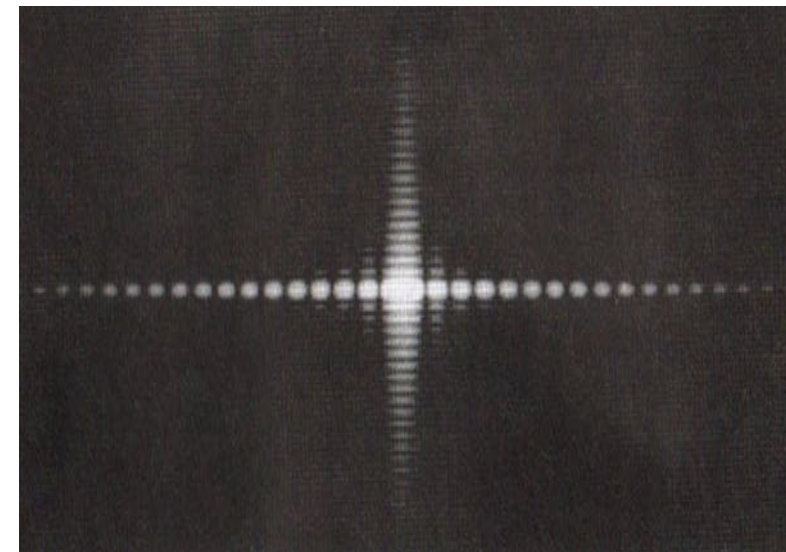
Common examples

Intensity integral, FT of aperture function	Solution	Definitions
Single slit: $I(\theta_x) = E_{res}(\theta_x) ^2 = \left \int_{-a/2}^{a/2} A_0 \exp[-ikx_s \sin \theta_x] dx_s \right ^2$	$I = A_0^2 \frac{\sin^2 \alpha}{\alpha^2}$ 	$\alpha = \frac{\pi}{\lambda} a \sin \theta_x$
Double slit: $I(\theta_x) = \left \int_{-b/2-a}^{-b/2} A(x_s) \exp[-ikx_s \sin \theta_x] dx_s + \int_{b/2}^{b/2+a} A(x_s) \exp[-ikx_s \sin \theta_x] dx_s \right ^2$	$I = A_0^2 \frac{\sin^2 \alpha}{\alpha^2} \cos^2 \frac{\delta}{2}$ 	$\alpha = \frac{\pi}{\lambda} a \sin \theta_x \text{ and } \delta = \frac{2\pi}{\lambda} (a+b) \sin \theta_x$
N-slit grating $I(\theta_x) = \left \int_{-a/2}^{a/2} A e^{-ikx_s \sin \theta_x} dx_s + \int_{d-a/2}^{d+a/2} A e^{-ikx_s \sin \theta_x} dx_s + \int_{2d-a/2}^{2d+a/2} A e^{-ikx_s \sin \theta_x} dx_s + \dots + \int_{(N-1)d-a/2}^{(N-1)d+a/2} A e^{-ikx_s \sin \theta_x} dx_s \right ^2$	$I = A_0^2 \frac{\sin^2 \alpha}{\alpha^2} \frac{\sin^2 N\beta}{\sin^2 \beta}$ 	$\alpha = \frac{\pi}{\lambda} a \sin \theta \text{ and } \beta = \frac{\delta}{2} = \frac{\pi}{\lambda} d \sin \theta$

- *Rectangular slit:*

$$I(\theta_x) = \left| \int_{-a/2}^{a/2} \int_{-b/2}^{b/2} A(x_s) \exp[-ikx_s \sin \theta_x] \exp[-iky_s \sin \theta_y] dx_s dy_s \right|^2$$

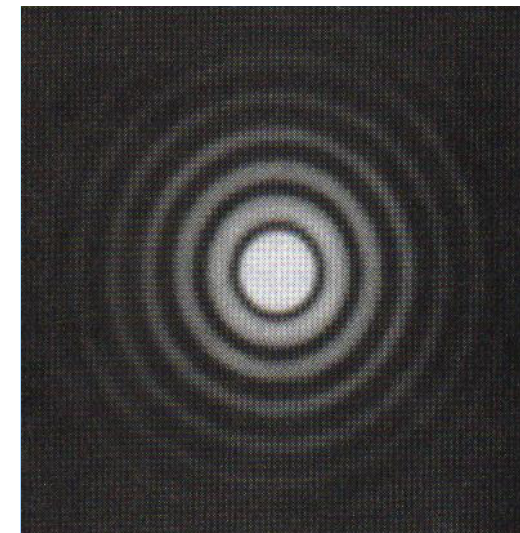
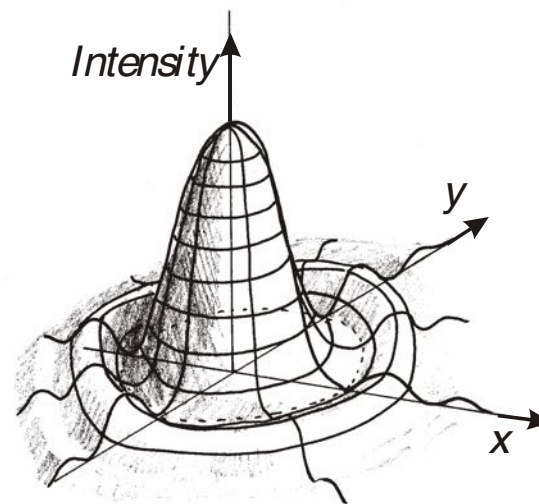
$$I = A_0^2 \frac{\sin^2 \alpha}{\alpha^2} \frac{\sin^2 \beta}{\beta^2}, \quad \text{where } \alpha = \frac{\pi}{\lambda} a \sin \theta_x \text{ and } \beta = \frac{\pi}{\lambda} b \sin \theta_y$$



- *Circular aperture:*

$$E_{res}(\rho_d, \theta_d) = \int_0^{\bar{\rho}} \int_0^{2\pi} A(x_s) \rho_s \exp\left[-\frac{ik}{L} \rho_s \cdot \rho_d \cdot \cos(\theta_s - \theta_d)\right] d\rho_s d\theta_s$$

$$E_{res} = A_0^2 \frac{J_1^2(\alpha)}{\alpha^2}, \quad \text{where } \alpha = \frac{ka\rho_d}{L} \quad \theta = \frac{1.22 \cdot \lambda}{\rho_d}$$

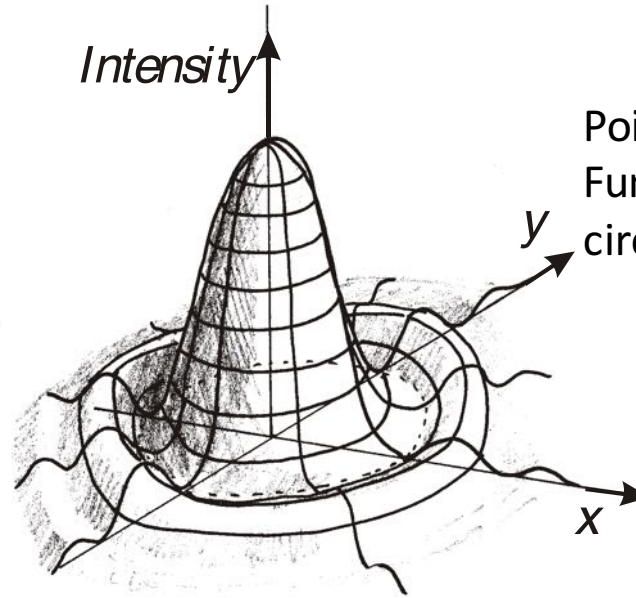


e.g. Telescope resolving power from PSF:

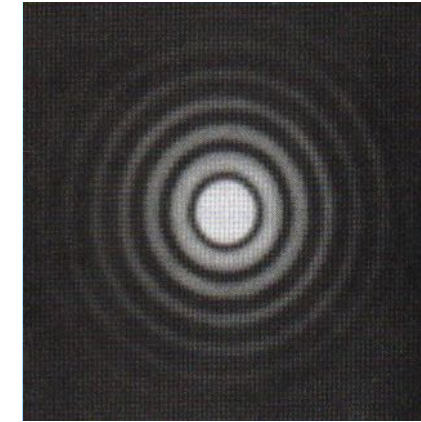
- In general the resolution is defined by the diffraction pattern which is the **Point Spread Function**
 - the response of an imaging system to a point source

$$E_{res} = A_0^2 \frac{J_1^2(\alpha)}{\alpha^2}, \text{ where } \alpha = \frac{ka\rho_d}{L}$$

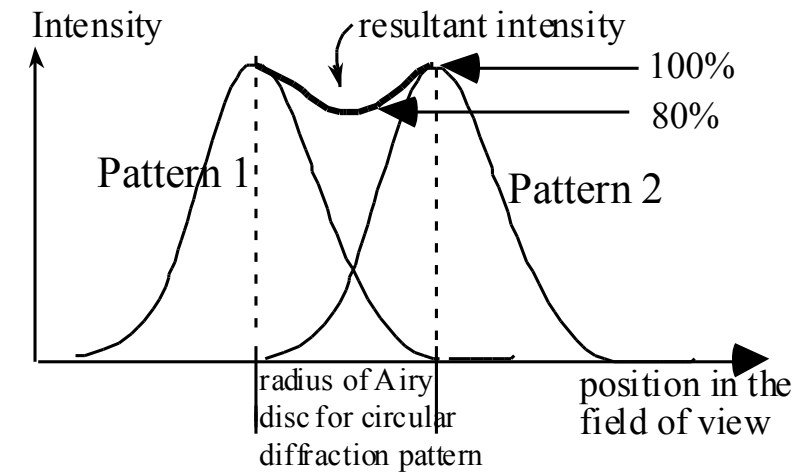
$$\theta = \frac{1.22 \cdot \lambda}{\rho_d}$$



Point Spread Function of a circular aperture



- When considering diffraction patterns or the diffraction limited case (e.g. viewing through a telescope) we use the **Rayleigh Criterion**:
- The **Rayleigh Criterion** states that two diffraction patterns with equal intensities may be said to be resolved when the central maximum of one pattern is not nearer than the position of the centre of the first minimum of the neighbouring pattern.



$$\sin \theta_R = \frac{\lambda}{a}$$

Single slit

$$\sin \theta_R = 1.22 \frac{\lambda}{a}$$

Circular aperture

Convolution visualized

- *The convolution function:*

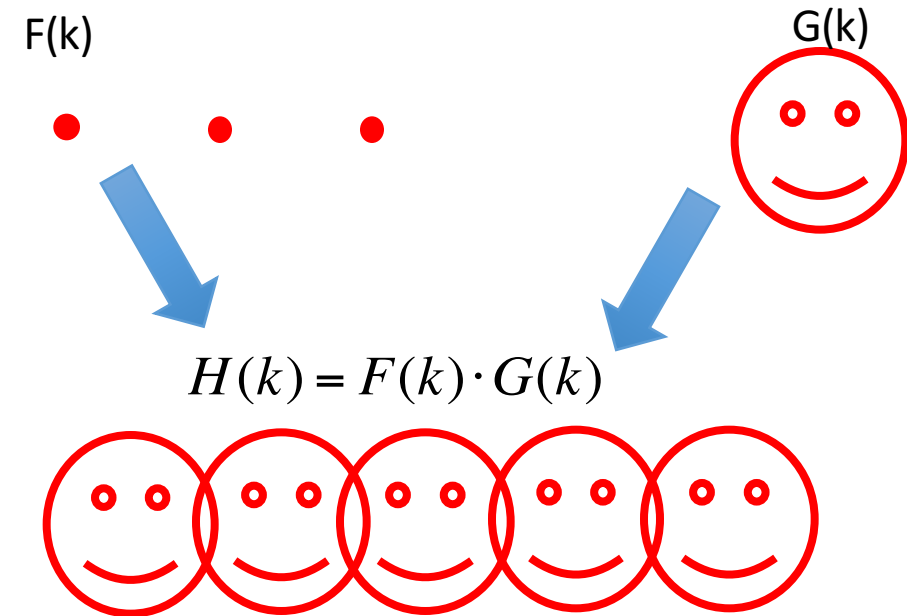
$$h(x) = f(x) \otimes g(x) = \int_{-\infty}^{\infty} f(x')g(x'-x) dx'$$

- *The convolution theorem:*

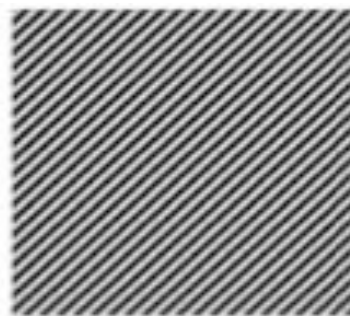
- F(k) is the Fourier Transform of f(x)
- G(k) is the Fourier Transform of g(x)
- H(k) is the Fourier Transform of h(x)
- Then:

$$H(k) = F(k) \cdot G(k)$$

- **The Fourier transform of a convolution of f and g is the product of the Fourier transforms of f and g**



Convolution theorem



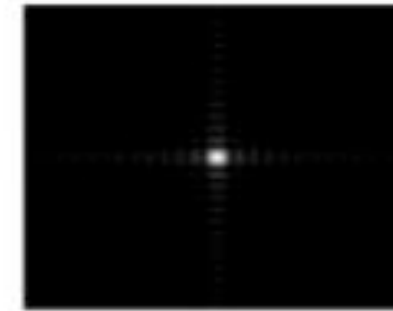
$f(x)$



$F(k)$



$g(x)$

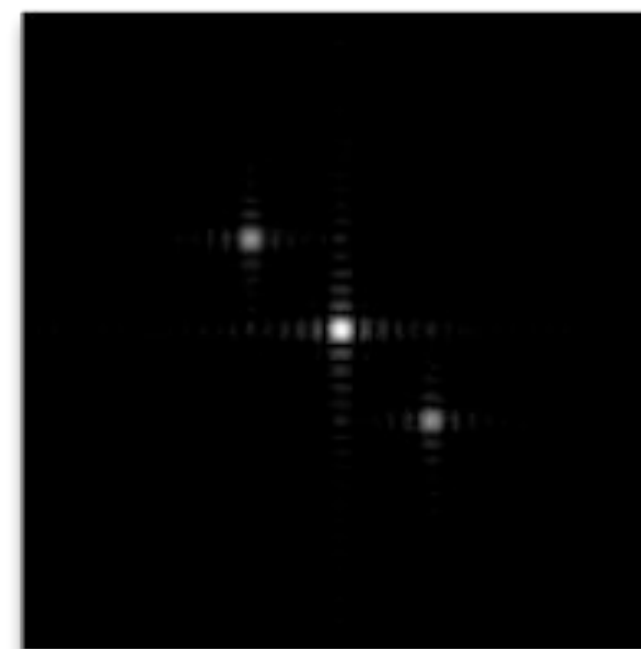
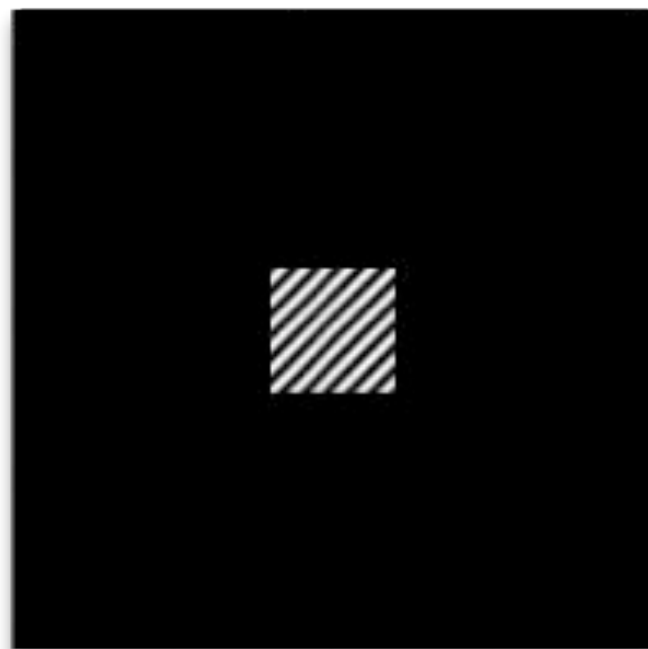


$G(k)$

multiplication

convolution

Spatial
domain

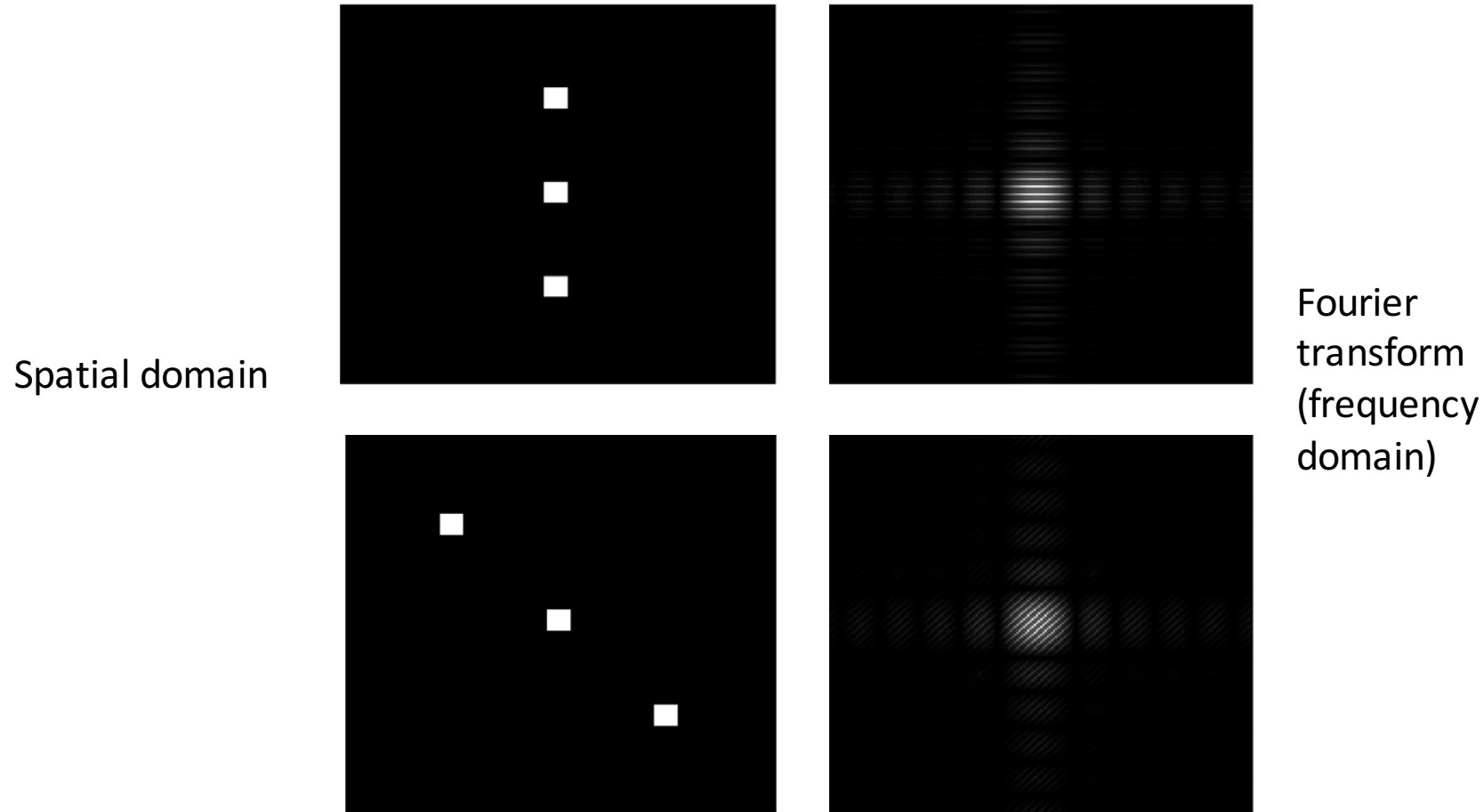


$$H(k) = F(k) \cdot G(k)$$

Fourier
transform
(frequency
domain)

Shift theorem in Fourier transform domain

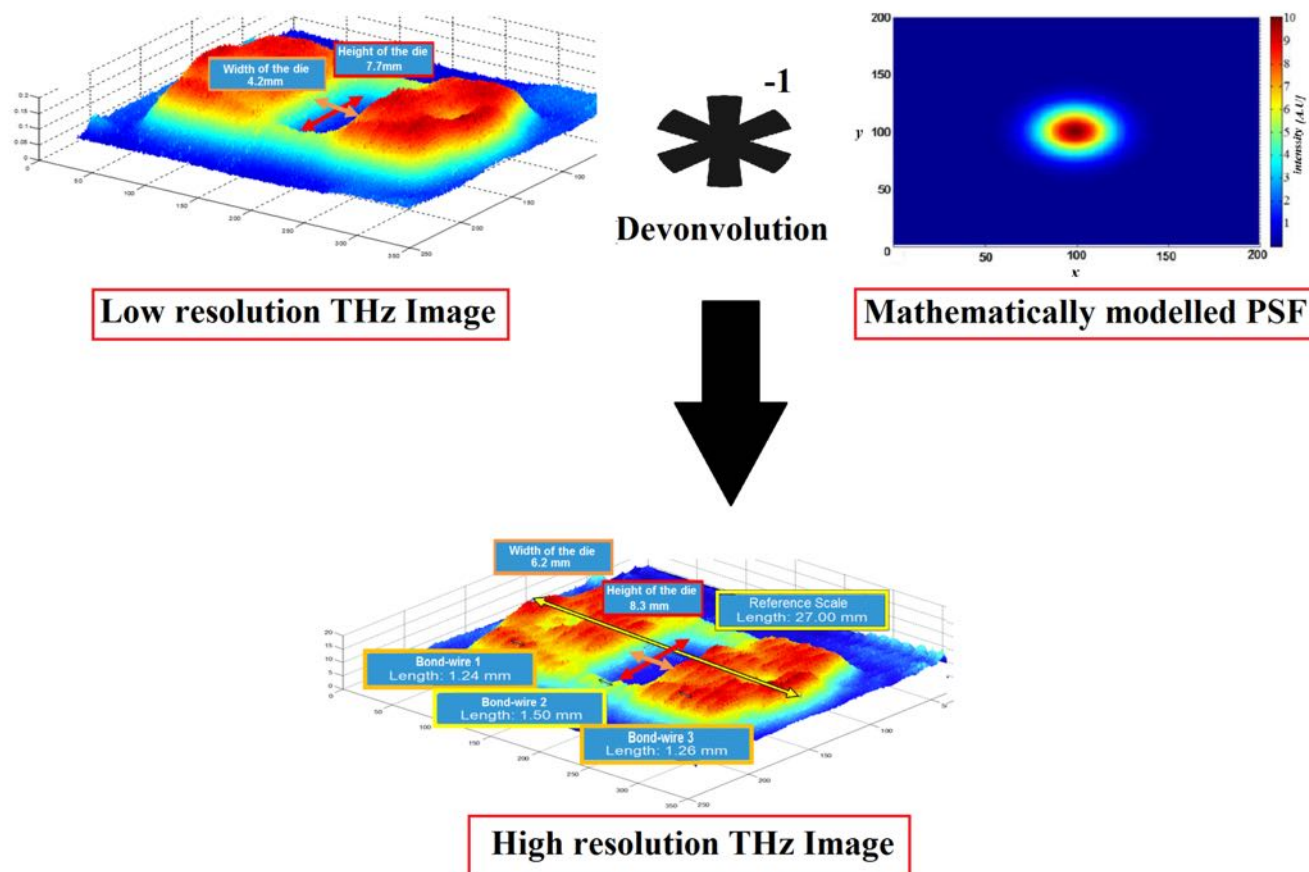
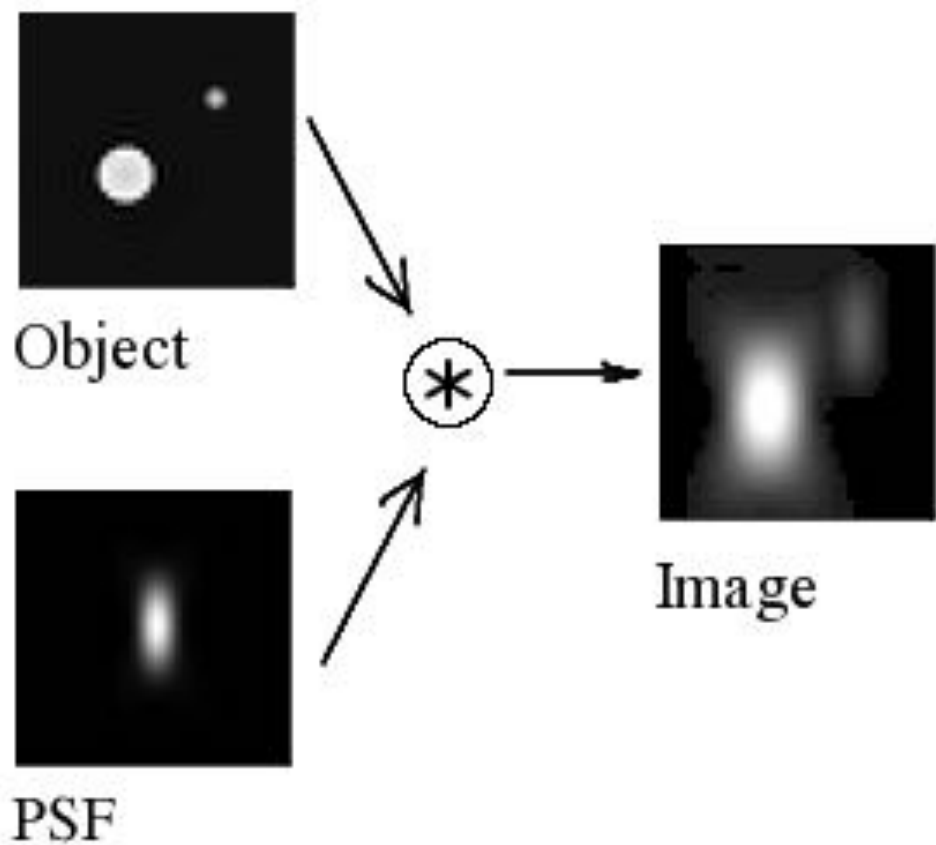
- The PSF is independent of position in the image plane (shift theorem)



$$\mathcal{F} \{g(x - a, y - b)\} = \exp \{2\pi (au + bv)\} G(u, v)$$

Deconvolution of the PSF

- The PSF is independent of position in the image plane (shift theorem), so a deconvolution can be applied to enhance the resolution of the image.



Deconvolution of PSF in medical imaging

- X-ray scintillator exhibits scattering which is modelled, then used to deconvolute a chest X-ray:

$I * PSF = B$, $I = B * PSF^{-1}$
 I = clear image, B = blurred image, PSF = point spread function, PSF^{-1} = inverse PSF, $*$ = convolution

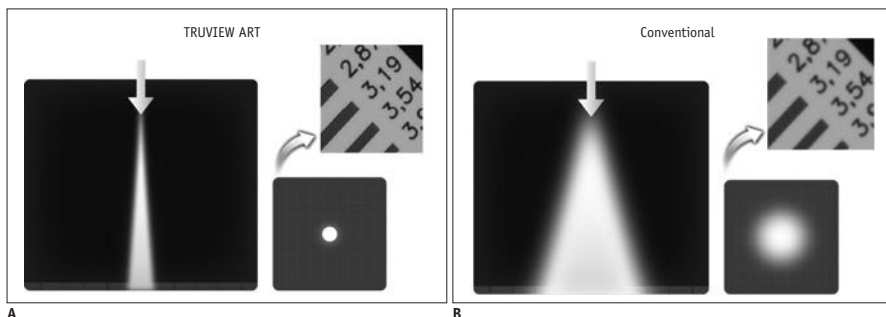
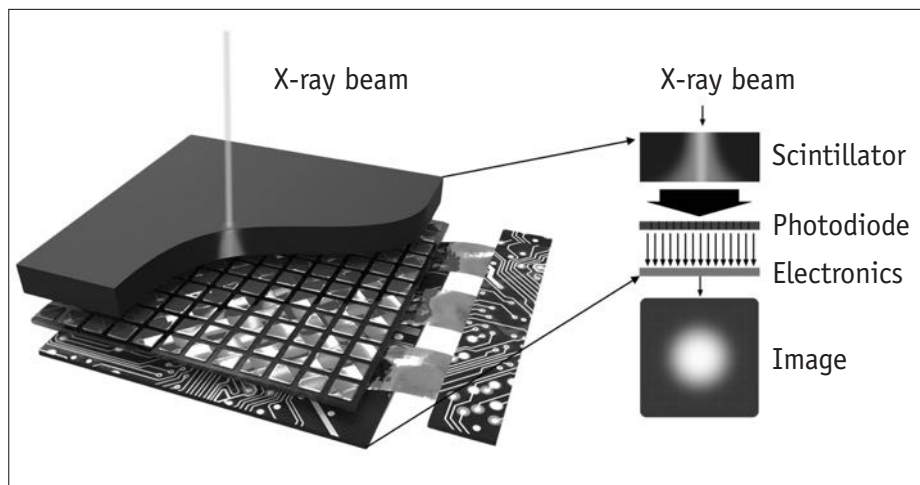


Fig. 2. Reconstructed image with and without TRUIVIEW ART (DRTECH Corp.).
A. By elimination of scattering effects applying TRUIVIEW ART, blurred image can be seen more clearly. **B.** Without TRUIVIEW ART, light scattering occurs by light spread of conventional scintillator, and image looks blurred.



Fig. 3. 75-year-old man with coronary artery disease.

Compared with original chest radiography (A), TRUIVIEW ART applied chest radiography (B) shows better depiction in overall image quality.

Application of Deconvolution Algorithm of Point Spread Function in Improving Image Quality: An Observer Preference Study on Chest Radiography

Kum Ju Chae, MD^{1,2}, Jin Mo Goo, MD, PhD^{1,3}, Su Yeon Ahn, MD¹, Jin Young Yoo, MD¹, Soon Ho Yoon, MD^{1,3}

Korean J Radiol 2018;19(1):147-152

PSF for pin-hole measurements of synchrotron light

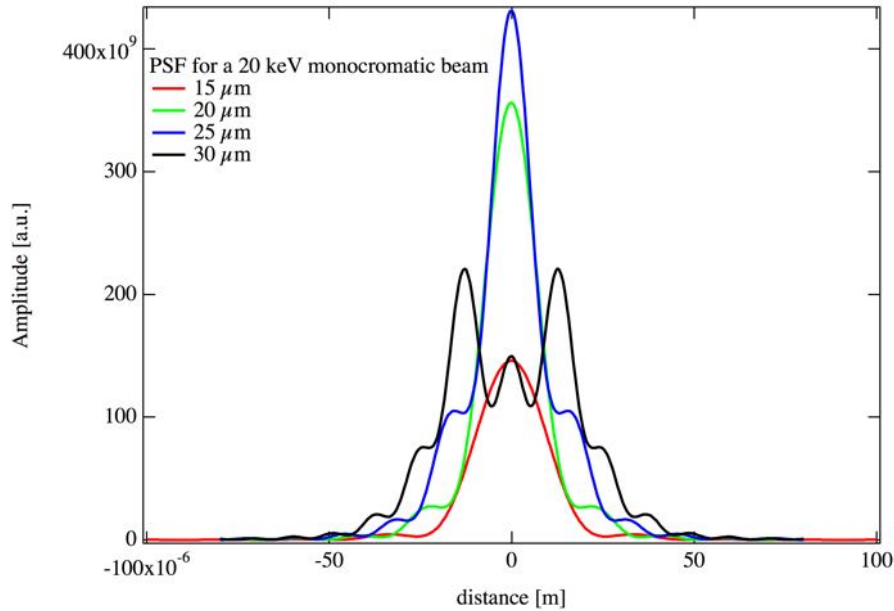
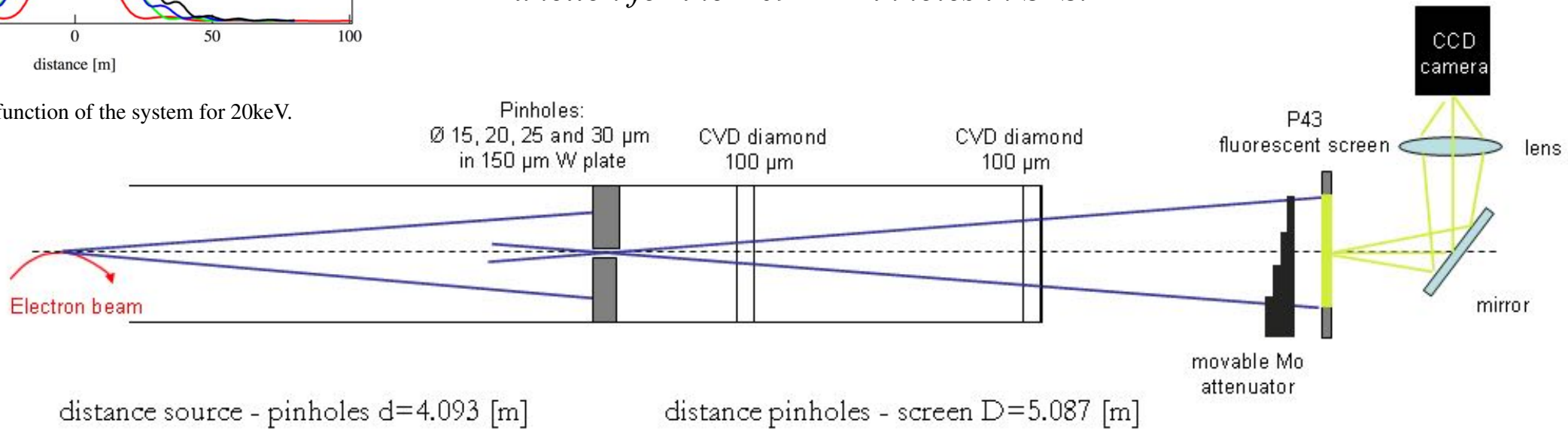


Figure 6: Point spread function of the system for 20keV.

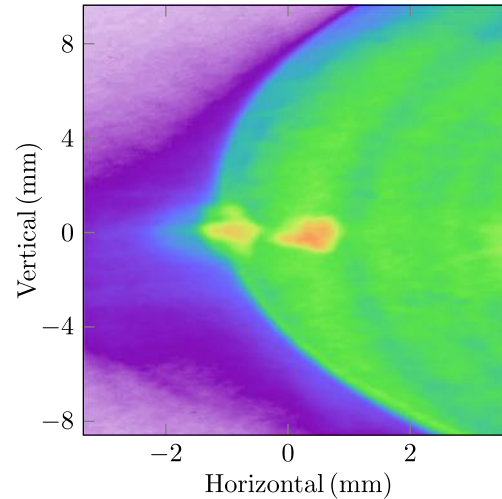
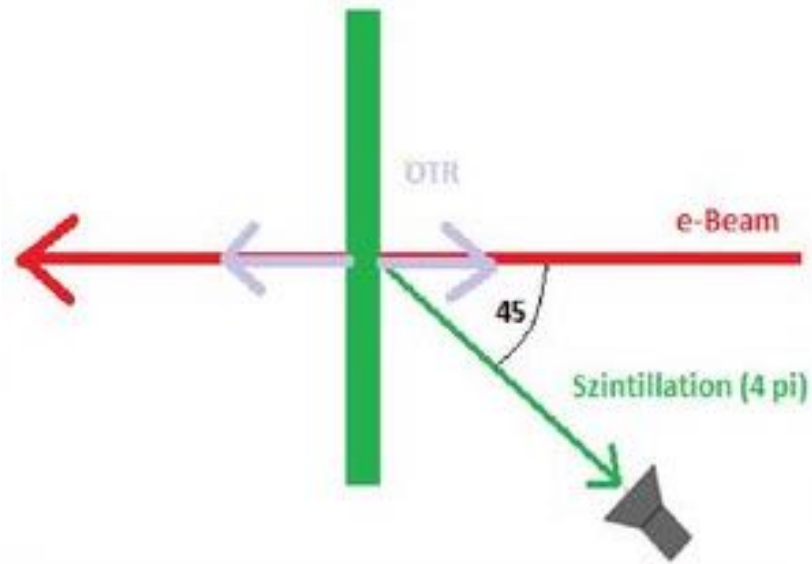
- PSF is dominated by diffraction at the pin-hole and Frensel pattern depends strongly on the pin-hole size, 15 -30 μm . [Swiss Lightsource, PSI]

Natalia Milas, Angela Saa Hernandez, *Calculation of the Point Spread Function for the X09DA Pinholes in SLS.*

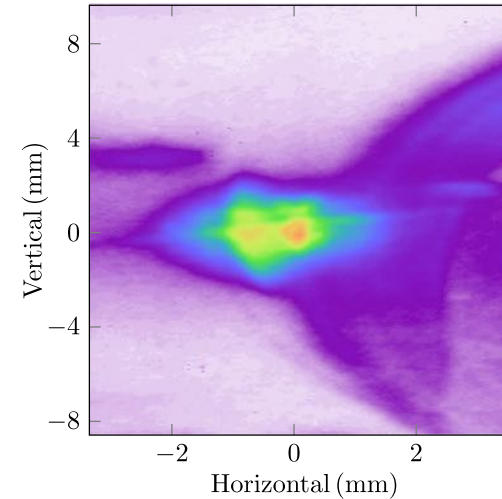


Background suppression:

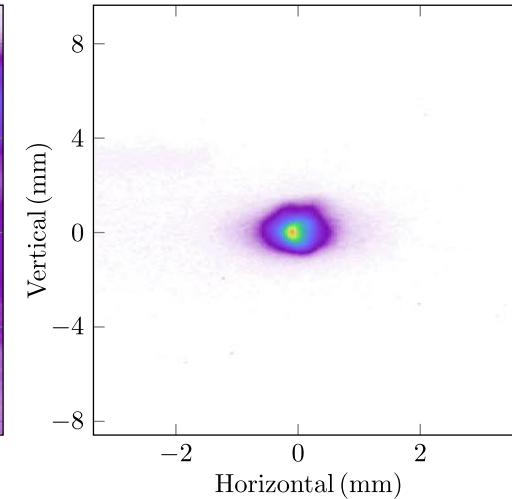
- OTR can be a source of background in scintillation light
- OTR background can be suppressed by changing the viewing geometry, so it is not reflected toward the camera:
- Or a gated camera can be used to distinguish the fast OTR from the delayed scintillation light.
- ICCD (a) and scintillation without (b) and with (c) delay:



(a) OTR screen, no time delay.



(b) LuAG screen, no time delay.



(c) LuAG screen, time delay.

Electron beam profile imaging in the presence of coherent optical radiation effects

Christopher Behrens,^{1,*} Christopher Gerth,¹ Gero Kube,¹ Bernhard Schmidt,¹ Stephan Wesch,¹ and Minjie Yan^{1,2}

Phys. Rev. ST Accel. Beams **15**, 062801 (2012)

- The observed distribution at the camera is a convoluted measure of the particle distribution:
 - The optical system must be calibrated and/or understood to map between the particle coordinate at the scintillator screen and the detector plane.
- Various optical technologies can help to improve image quality:
 - Scheimpflug geometry to obtain sharp focus over complete object plane.
 - Bi-telecentric lens to eliminate dependence of magnification on object (and image) distance, hence reducing image distortion.
 - Aberrations may be corrected by careful optical design in Zemax or similar software, e.g. by using achromatic, or catadioptric components.
- Resolution depends on the observation geometry, screen tilt and viewing angle.
- Measurement and/or calculation of the PSF allows a deconvolution of the image to enhance the resolution.

Thanks to Beate, Isabel and Peter for the excellent organization!